- Low Supply-Voltage Range, 1.8 V to 3.6 V
- **Ultralow-Power Consumption:**
 - Active Mode: 365 μA at 1 MHz, 2.2 V
 - Standby Mode (VLO): 0.5 μA
 - Off Mode (RAM Retention): 0.1 μA
- Wake-Up From Standby Mode in Less Than 1 µs
- 16-Bit RISC Architecture, 62.5-nsInstruction Cycle Time
- **Three-Channel Internal DMA**
- 12-Bit Analog-to-Digital (A/D) Converter With Internal Reference, Sample-and-Hold, and Autoscan Feature
- Dual 12-Bit Digital-to-Analog (D/A) **Converters With Synchronization**
- 16-Bit Timer A With Three Capture/Compare Registers
- 16-Bit Timer B With Seven Capture/Compare-With-Shadow Registers
- **On-Chip Comparator**
- **Four Universal Serial Communication** Interfaces (USCIs)
 - USCI A0 and USCI A1
 - Enhanced UART Supporting Auto-Baudrate Detection
 - IrDA Encoder and Decoder
 - Synchronous SPI
 - USCI B0 and USCI B1
 - I²C™
 - Synchronous SPI

- Supply Voltage Supervisor/Monitor With **Programmable Level Detection**
- **Brownout Detector**
- **Bootstrap Loader**
- Serial Onboard Programming, No External Programming Voltage Needed **Programmable Code Protection by Security Fuse**
- **Family Members Include:**
 - MSP430F2416: 92KB+256B Flash Memory, 4KB RAM
 - MSP430F2417: 92KB+256B Flash Memory, 8KB RAM
 - MSP430F2418: 116KB+256B Flash Memory, 8KB RAM
 - MSP430F2419: 120KB+256B Flash Memory, 4KB RAM
 - MSP430F2616: 92KB+256B Flash Memory, 4KB RAM
 - MSP430F2617: 92KB+256B Flash Memory, 8KB RAM
 - MSP430F2618: 116KB+256B Flash Memory, 8KB RAM - MSP430F2619:
 - 120KB+256B Flash Memory, 4KB RAM
- Available in 80-Pin Quad Flat Pack (QFP) and 64-Pin QFP (See Available Options)
- For Complete Module Descriptions, See the MSP430x2xx Family User's Guide, **Literature Number SLAU144**

description

The Texas Instruments MSP430 family of ultralow-power microcontrollers consists of several devices featuring different sets of peripherals targeted for various applications. The architecture, combined with five low-power modes is optimized to achieve extended battery life in portable measurement applications. The device features a powerful 16-bit RISC CPU, 16-bit registers, and constant generators that contribute to maximum code efficiency. The calibrated digitally controlled oscillator (DCO) allows wake-up from low-power modes to active mode in less than 1 μ s.

The MSP430F261x/241x series are microcontroller configurations with two built-in 16-bit timers, a fast 12-bit A/D converter, a comparator, dual 12-bit D/A converters, four universal serial communication interface (USCI) modules, DMA, and up to 64 I/O pins. The MSP430F241x devices are identical to the MSP430F261x devices, with the exception that the DAC12 and the DMA modules are not implemented.

Typical applications include sensor systems, industrial control applications, hand-held meters, etc.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

I²C is a registered trademark of Philips Incorporated.



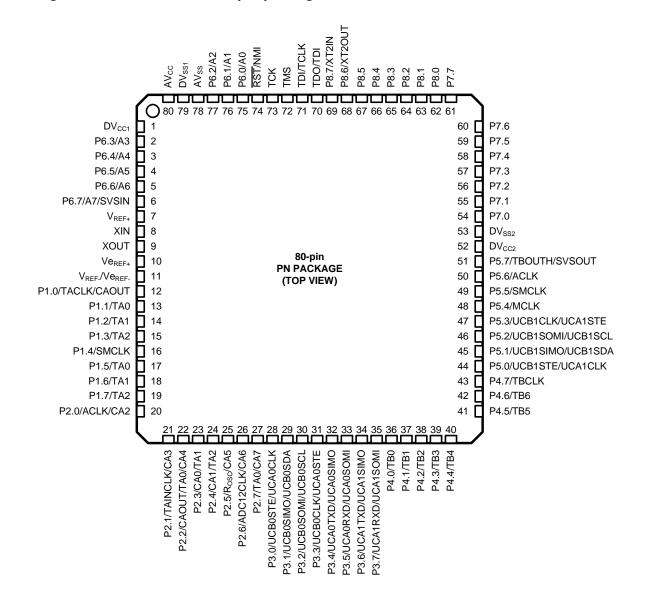
[†] The MSP430F241x devices are identical to the MSP430F261x devices, with the exception that the DAC12 modules and the DMA controller are not implemented.

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

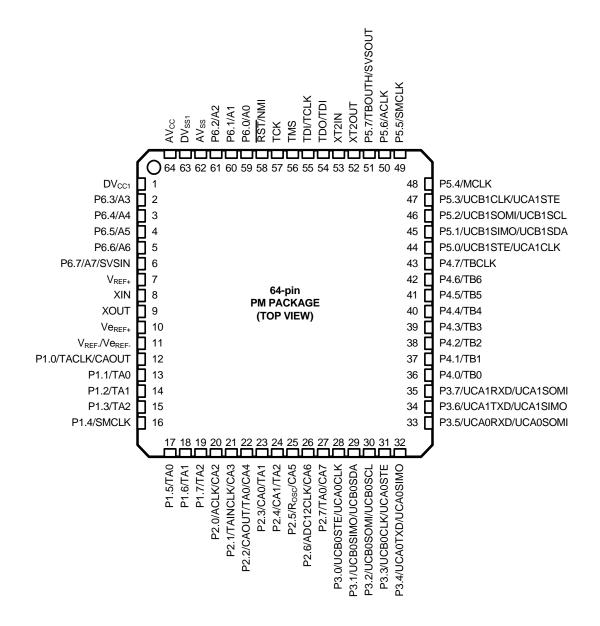
AVAILABLE OPTIONS

-	PACKAGED DEVICES					
T _A	PLASTIC 80-PIN LQFP (PN)	PLASTIC 64-PIN LQFP (PM)				
	MSP430F2416TPN	MSP430F2416TPM				
	MSP430F2417TPN	MSP430F2417TPM				
	MSP430F2418TPN	MSP430F2418TPM				
-40°C to 105°C	MSP430F2419TPN	MSP430F2419TPM				
-40°C to 105°C	MSP430F2616TPN	MSP430F2616TPM				
	MSP430F2617TPN	MSP430F2617TPM				
	MSP430F2618TPN	MSP430F2618TPM				
	MSP430F2619TPN	MSP430F2619TPM				

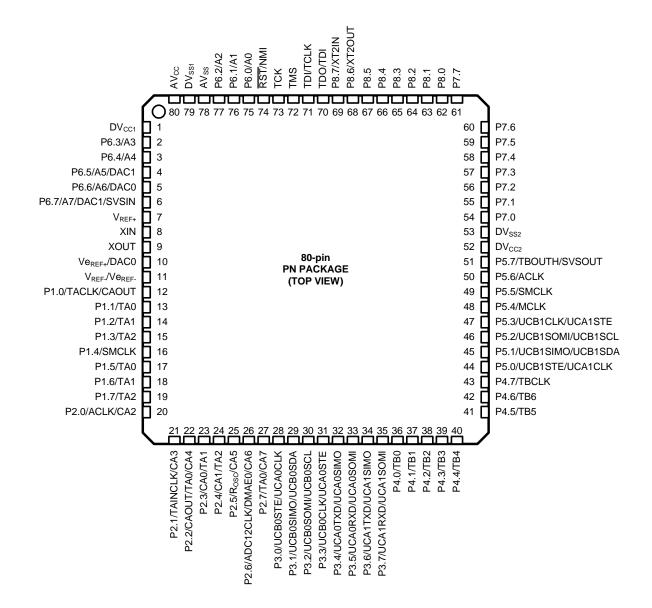
pin designation, MSP430F241x, 80-pin package



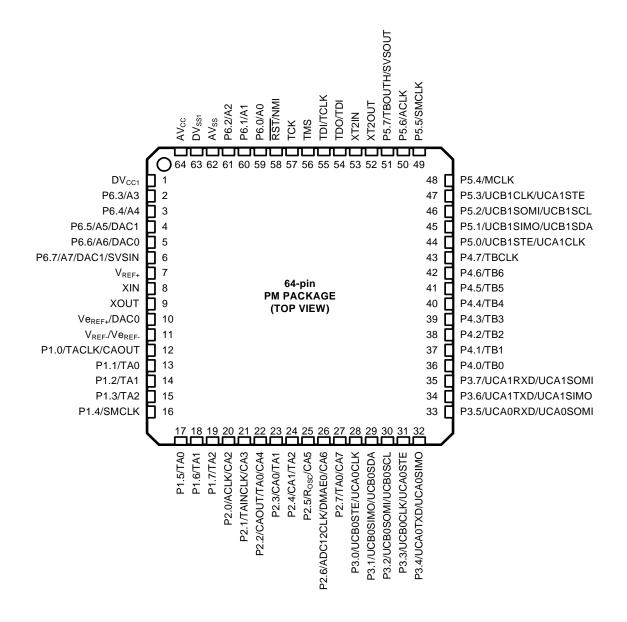
pin designation, MSP430F241x, 64-pin package



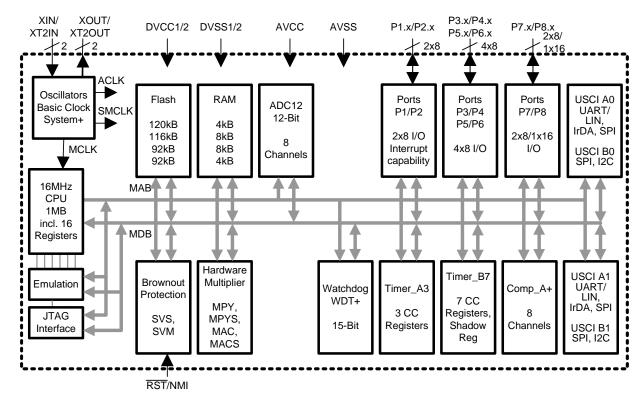
pin designation, MSP430F261x, 80-pin package



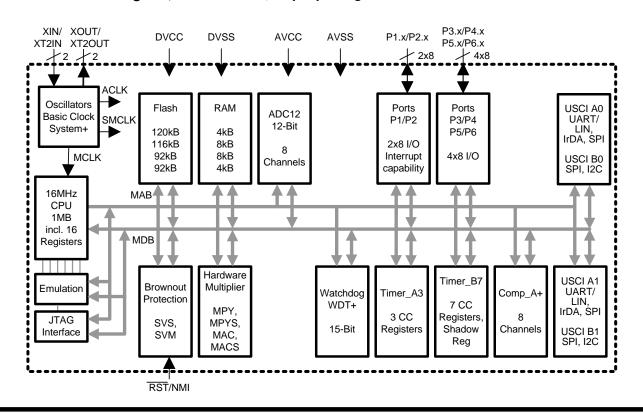
pin designation, MSP430F261x, 64-pin package



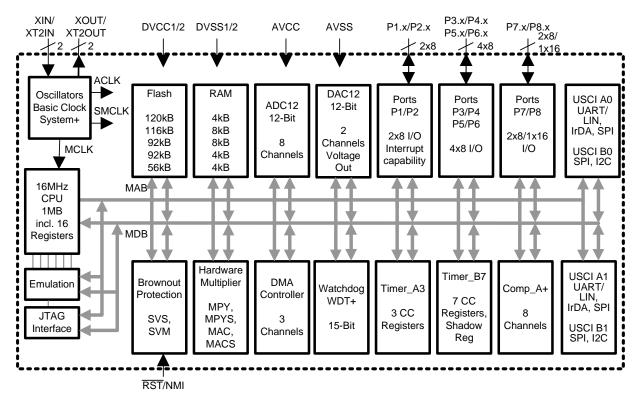
functional block diagram, MSP430F241x, 80-pin package



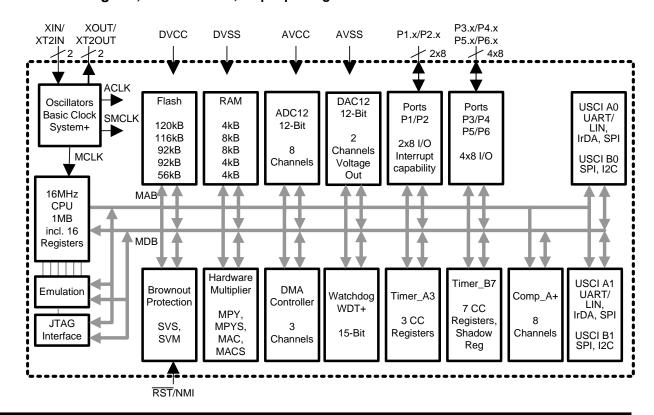
functional block diagram, MSP430F241x, 64-pin package



functional block diagram, MSP430F261x, 80-pin package



functional block diagram, MSP430F261x, 64-pin package





Terminal Functions

TERMINAL						
	NO.		NO.		I/O	DESCRIPTION
NAME	64 PIN	80 PIN	1/0	DESCRIPTION		
AV _{CC}	64	80		Analog supply voltage, positive terminal. Supplies only the analog portion of ADC12 and DAC12.		
AV _{SS}	62	78		Analog supply voltage, negative terminal. Supplies only the analog portion of ADC12 and DAC12.		
DV _{CC1}	1	1		Digital supply voltage, positive terminal. Supplies all digital parts.		
DV _{SS1}	63	79		Digital supply voltage, negative terminal. Supplies all digital parts.		
DV _{CC2}		52		Digital supply voltage, positive terminal. Supplies all digital parts.		
DV _{SS2}		53		Digital supply voltage, negative terminal. Supplies all digital parts.		
P1.0/TACLK/ CAOUT	12	12	I/O	General-purpose digital I/O pin/Timer_A, clock signal TACLK input/Comparator_A output		
P1.1/TA0	13	13	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI0A input, compare: Out0 output/BSL transmit		
P1.2/TA1	14	14	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI1A input, compare: Out1 output		
P1.3/TA2	15	15	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI2A input, compare: Out2 output		
P1.4/SMCLK	16	16	I/O	General-purpose digital I/O pin/SMCLK signal output		
P1.5/TA0	17	17	I/O	General-purpose digital I/O pin/Timer_A, compare: Out0 output		
P1.6/TA1	18	18	I/O	General-purpose digital I/O pin/Timer_A, compare: Out1 output		
P1.7/TA2	19	19	I/O	General-purpose digital I/O pin/Timer_A, compare: Out2 output		
P2.0/ACLK/CA2	20	20	I/O	General-purpose digital I/O pin/ACLK output/Comparator_A input		
P2.1/TAINCLK/ CA3	21	21	I/O	General-purpose digital I/O pin/Timer_A, clock signal at INCLK		
P2.2/CAOUT/ TA0/CA4	22	22	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI0B input/Comparator_A output/BSL receive/Comparator_A input		
P2.3/CA0/TA1	23	23	I/O	General-purpose digital I/O pin/Timer_A, compare: Out1 output/Comparator_A input		
P2.4/CA1/TA2	24	24	I/O	General-purpose digital I/O pin/Timer_A, compare: Out2 output/Comparator_A input		
P2.5/Rosc/CA5	25	25	I/O	General-purpose digital I/O pin/input for external resistor defining the DCO nominal frequency/Comparator_A input		
P2.6/ADC12CLK/ DMAE0†/CA6	26	26	I/O	General-purpose digital I/O pin/conversion clock – 12-bit ADC/DMA channel 0 external trigger/Comparator_A input		
P2.7/TA0/CA7	27	27	I/O	General-purpose digital I/O pin/Timer_A, compare: Out0 output/Comparator_A input		
P3.0/UCB0STE/ UCA0CLK	28	28	I/O	General-purpose digital I/O pin/USCI B0 slave transmit enable/USCI A0 clock input/output		
P3.1/UCB0SIMO/ UCB0SDA	29	29	I/O	General-purpose digital I/O pin/USCI B0 slave in/master out in SPI mode, SDA I ² C data in I ² C mode		
P3.2/UCB0SOMI/ UCB0SCL	30	30	I/O	General-purpose digital I/O pin/USCI B0 slave out/master in in SPI mode, SCL I ² C clock in I ² C mode		
P3.3/UCB0CLK/ UCA0STE	31	31	I/O	General-purpose digital I/O/USCI B0 clock input/output, USCI A0 slave transmit enable		
P3.4/UCA0TXD/ UCA0SIMO	32	32	I/O	General-purpose digital I/O pin/USCIA transmit data output in UART mode, slave data in/master out in SPI mode		
P3.5/UCA0RXD/ UCA0SOMI	33	33	I/O	General-purpose digital I/O pin/USCI A0 receive data input in UART mode, slave data out/master in in SPI mode		
P3.6/UCA1TXD/ UCA1SIMO	34	34	I/O	General-purpose digital I/O pin/USCI A1 transmit data output in UART mode, slave data in/master out in SPI mode		
P3.7/UCA1RXD/ UCA1SOMI	35	35	I/O	General-purpose digital I/O pin/USCIA1 receive data input in UART mode, slave data out/master in in SPI mode		

[†] MSP430F261x devices only



Terminal Functions (Continued)

TERMINAL							
	N	0.	I/O	DESCRIPTION			
NAME	64 PIN	80 PIN	1/0	DESCRIPTION			
P4.0/TB0	36	36	I/O	General-purpose digital I/O pin/Timer_B, capture: CCI0A/B input, compare: Out0 output			
P4.1/TB1	37	37	I/O	General-purpose digital I/O pin/Timer_B, capture: CCI1A/B input, compare: Out1 output			
P4.2/TB2	38	38	I/O	General-purpose digital I/O pin/Timer_B, capture: CCI2A/B input, compare: Out2 output			
P4.3/TB3	39	39	I/O	General-purpose digital I/O pin/Timer_B, capture: CCl3A/B input, compare: Out3 output			
P4.4/TB4	40	40	I/O	General-purpose digital I/O pin/Timer_B, capture: CCI4A/B input, compare: Out4 output			
P4.5/TB5	41	41	I/O	General-purpose digital I/O pin/Timer_B, capture: CCI5A/B input, compare: Out5 output			
P4.6/TB6	42	42	I/O	General-purpose digital I/O pin/Timer_B, capture: CCI6A input, compare: Out6 output			
P4.7/TBCLK	43	43	I/O	General-purpose digital I/O pin/Timer_B, clock signal TBCLK input			
P5.0/UCB1STE/ UCA1CLK	44	44	I/O	General-purpose digital I/O pin/USCI B1 slave transmit enable/USCI A1 clock input/output			
P5.1/UCB1SIMO/ UCB1SDA	45	45	I/O	General-purpose digital I/O pin/USCI B1slave in/master out in SPI mode, SDA I ² C data in I ² C mode			
P5.2/UCB1SOMI/ UCB1SCL	46	46	I/O	General-purpose digital I/O pin/USCI B1slave out/master in in SPI mode, SCL I ² C clock in I ² C mode			
P5.3/UCB1CLK/ UCA1STE	47	47	I/O	General-purpose digital I/O/USCI B1 clock input/output, USCI A1 slave transmit enable			
P5.4/MCLK	48	48	I/O	General-purpose digital I/O pin/main system clock MCLK output			
P5.5/SMCLK	49	49	I/O	General-purpose digital I/O pin/submain system clock SMCLK output			
P5.6/ACLK	50	50	I/O	General-purpose digital I/O pin/auxiliary clock ACLK output			
P5.7/TBOUTH/ SVSOUT	51	51	I/O	General-purpose digital I/O pin/switch all PWM digital output ports to high impedance - Timer_B TB0 to TB6/SVS comparator output			
P6.0/A0	59	75	I/O	General-purpose digital I/O pin/analog input A0 – 12-bit ADC			
P6.1/A1	60	76	I/O	General-purpose digital I/O pin/analog input A1 – 12-bit ADC			
P6.2/A2	61	77	I/O	General-purpose digital I/O pin/analog input A2 – 12-bit ADC			
P6.3/A3	2	2	I/O	General-purpose digital I/O pin/analog input A3 – 12-bit ADC			
P6.4/A4	3	3	I/O	General-purpose digital I/O pin/analog input A4 – 12-bit ADC			
P6.5/A5/DAC1 [†]	4	4	I/O	General-purpose digital I/O pin/analog input A5 – 12-bit ADC/DAC12.1 output			
P6.6/A6/DAC0 [†]	5	5	I/O	General-purpose digital I/O pin/analog input A6 – 12-bit ADC/DAC12.0 output			
P6.7/A7/DAC1 [†] / SVSIN	6	6	I/O	General-purpose digital I/O pin/analog input a7 – 12-bit ADC/DAC12.1 output/SVS input			
P7.0		54	I/O	General-purpose digital I/O pin			
P7.1		55	I/O	General-purpose digital I/O pin			
P7.2		56	I/O	General-purpose digital I/O pin			
P7.3		57	I/O	General-purpose digital I/O pin			
P7.4		58	I/O	General-purpose digital I/O pin			
P7.5		59	I/O	General-purpose digital I/O pin			
P7.6		60	I/O	General-purpose digital I/O pin			
P7.7		61	I/O	General-purpose digital I/O pin			
P8.0		62	I/O	General-purpose digital I/O pin			
P8.1		63	I/O	General-purpose digital I/O pin			
P8.2		64	I/O	General-purpose digital I/O pin			
P8.3		65	I/O	General-purpose digital I/O pin			

[†] MSP430F261x devices only



Terminal Functions (Continued)

TERMIN	IAL				
	N	0.	1/0	DESCRIPTION	
NAME	64 PIN	80 PIN	1/0	DESCRIPTION	
P8.4		66	I/O	General-purpose digital I/O pin	
P8.5		67	I/O	General-purpose digital I/O pin	
P8.6/XT2OUT		68	0	General-purpose digital I/O pin/Output terminal of crystal oscillator XT2	
P8.7/XT2IN		69	I	General-purpose digital I/O pin/Input port for crystal oscillator XT2. Only standard crystals can be connected.	
XT2OUT	52		0	Output terminal of crystal oscillator XT2	
XT2IN	53		I	Input port for crystal oscillator XT2	
RST/NMI	58	74	I	Reset input, nonmaskable interrupt input port, or bootstrap loader start (in flash devices).	
TCK	57	73	I	Test clock (JTAG). TCK is the clock input port for device programming test and bootstrap loader start.	
TDI/TCLK	55	71	I	Test data input or test clock input. The device protection fuse is connected to TDI/TCLK.	
TDO/TDI	54	70	I/O	Test data output port. TDO/TDI data output or programming data input terminal.	
TMS	56	72	I	Test mode select. TMS is used as an input port for device programming and test.	
Ve _{REF+} /DAC0 [†]	10	10	I	Input for an external reference voltage/DAC12.0 output	
V _{REF+}	7	7	0	Output of positive terminal of the reference voltage in the ADC12	
V _{REF-} /Ve _{REF-}	11	11	I	Negative terminal for the reference voltage for both sources, the internal reference voltage, or external applied reference voltage	
XIN	8	8	I	Input port for crystal oscillator XT1. Standard or watch crystals can be connected.	
XOUT	9	9	0	Output port for crystal oscillator XT1. Standard or watch crystals can be connected.	

[†] MSP430F261x devices only

short-form description

CPU

The MSP430 CPU has a 16-bit RISC architecture that is highly transparent to the application. All operations, other than program-flow instructions, are performed as register operations in conjunction with seven addressing modes for source operand and four addressing modes for destination operand.

The CPU is integrated with 16 registers that provide reduced instruction execution time. The register-to-register operation execution time is one cycle of the CPU clock.

Four of the registers, R0 to R3, are dedicated as program counter, stack pointer, status register, and constant generator, respectively. The remaining registers are general-purpose registers.

Peripherals are connected to the CPU using data, address, and control buses, and can be handled with all instructions.

instruction set

The instruction set consists of 51 instructions with three formats and seven address modes. Each instruction can operate on word and byte data. Table 1 shows examples of the three types of instruction formats; the address modes are listed in Table 2.



Table 1. Instruction Word Formats

Dual operands, source-destination	e.g., ADD R4,R5	R4 + R5> R5
Single operands, destination only	e.g., CALL R8	PC>(TOS), R8> PC
Relative jump, un/conditional	e.g., JNE	Jump-on-equal bit = 0

Table 2. Address Mode Descriptions

ADDRESS MODE	s	D	SYNTAX	EXAMPLE	OPERATION
Register	•	•	MOV Rs,Rd	MOV R10,R11	R10> R11
Indexed	•	•	MOV X(Rn),Y(Rm)	MOV 2(R5),6(R6)	M(2+R5)> M(6+R6)
Symbolic (PC relative)	•	•	MOV EDE,TONI		M(EDE)> M(TONI)
Absolute	•	•	MOV &MEM,&TCDAT		M(MEM)> M(TCDAT)
Indirect	•		MOV @Rn,Y(Rm)	MOV @R10,Tab(R6)	M(R10)> M(Tab+R6)
Indirect autoincrement	•		MOV @Rn+,Rm	MOV @R10+,R11	M(R10)> R11 R10 + 2> R10
Immediate	•		MOV #X,TONI	MOV #45,TONI	#45> M(TONI)

NOTE: S = source D = destination



operating modes

The MSP430 has one active mode and five software selectable low-power modes of operation. An interrupt event can wake up the device from any of the five low-power modes, service the request, and restore back to the low-power mode on return from the interrupt program.

The following six operating modes can be configured by software:

- Active mode (AM)
 - All clocks are active.
- Low-power mode 0 (LPM0)
 - CPU is disabled.
 ACLK and SMCLK remain active. MCLK is disabled.
- Low-power mode 1 (LPM1)
 - CPU is disabled.
 ACLK and SMCLK remain active. MCLK is disabled.
 DCO's dc-generator is disabled if DCO not used in active mode.
- Low-power mode 2 (LPM2)
 - CPU is disabled.
 MCLK and SMCLK are disabled.
 DCO's dc-generator remains enabled.
 ACLK remains active.
- Low-power mode 3 (LPM3)
 - CPU is disabled.
 MCLK and SMCLK are disabled.
 DCO's dc-generator is disabled.
 ACLK remains active.
- Low-power mode 4 (LPM4)
 - CPU is disabled.
 ACLK is disabled.
 MCLK and SMCLK are disabled.
 DCO's dc-generator is disabled.
 Crystal oscillator is stopped.

interrupt vector addresses

The interrupt vectors and the power-up starting address are located in the address range 0x0FFFF to 0x0FFC0. The vector contains the 16-bit address of the appropriate interrupt-handler instruction sequence. If the reset vector (0x0FFFE) contains 0xFFFF (e.g., flash is not programmed), the CPU enters LPM4 after power-up.

INTERRUPT SOURCE	INTERRUPT FLAG	SYSTEM INTERRUPT	WORD ADDRESS	PRIORITY	
Power-up External Reset Watchdog Flash Key Violation PC out of range (see Note 1)	PORIFG WDTIFG RSTIFG KEYV (see Note 2)	Reset	0x0FFFE	31, highest	
NMI Oscillator Fault Flash memory access violation	NMIIFG OFIFG ACCVIFG (see Notes 2 and 6)	(Non)maskable (Non)maskable (Non)maskable	0x0FFFC	30	
Timer_B7	TBCCR0 CCIFG (see Note 3)	Maskable	0x0FFFA	29	
Timer_B7	TBCCR1 to TBCCR6 CCIFGs, TBIFG (see Notes 2 and 3)	Maskable	0x0FFF8	28	
Comparator_A+	CAIFG	Maskable	0x0FFF6	27	
Watchdog timer+	WDTIFG	Maskable	0x0FFF4	26	
Timer_A3	TACCR0 CCIFG (see Note 3)	Maskable	0x0FFF2	25	
Timer_A3	TACCR1 CCIFG TACCR2 CCIFG TAIFG (see Notes 2 and 3)	Maskable	0x0FFF0	24	
USCI_A0/USCI_B0 receive USCI_B0 I2C status	UCA0RXIFG, UCB0RXIFG (see Notes 2 and 4)	Maskable	0x0FFEE	23	
USCI_A0/USCI_B0 transmit USCI_B0 I2C receive/transmit	UCA0TXIFG, UCB0TXIFG (see Note 2 and 4)	Maskable	0x0FFEC	22	
ADC12	ADC12IFG (see Notes 2 and 3)	Maskable	0x0FFEA	21	
			0x0FFE8	20	
I/O port P2 (eight flags)	P2IFG.0 to P2IFG.7 (see Notes 2 and 3)	Maskable	0x0FFE6	19	
I/O port P1 (eight flags)	P1IFG.0 to P1IFG.7 (see Notes 2 and 3)	Maskable	0x0FFE4	18	
USCI_A0/USCI_B1 receive USCI_B1 I2C status	UCA1RXIFG, UCB1RXIFG (see Notes 2 and 4)	Maskable	0x0FFE2	17	
USCI_A1/USCI_B1 transmit USCI_B1 I2C receive/transmit	UCA1TXIFG, UCB1TXIFG (see Notes 2 and 5)	Maskable	0x0FFE0	16	
DMA	DMA0IFG, DMA1IFG, DMA2IFG (see Notes 2 and 3)	Maskable	0x0FFDE	15	
DAC12	DAC12_0IFG, DAC12_1IFG (see Notes 2 and 3)	Maskable	0x0FFDC	14	
Reserved (see Notes 7 and 8)	Reserved		0x0FFDA to 0x0FFC0	13 to 0, lowest	

NOTES: 1. A reset is executed if the CPU tries to fetch instructions from within the module register memory address range (0x00000 to 0x001FF) or from within unused address ranges.

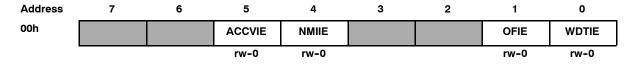
- 2. Multiple source flags.
- 3. Interrupt flags are located in the module.
- 4. In SPI mode: UCB0RXIFG. In I2C mode: UCALIFG, UCNACKIFG, ICSTTIFG, UCSTPIFG.
- 5. In UART/SPI mode: UCB0TXIFG. In I2C mode: UCB0RXIFG, UCB0TXIFG.
- 6. (Non)maskable: The individual interrupt-enable bit can disable an interrupt event, but the general-interrupt enable cannot.
- 7. The address 0x0FFBE is used as bootstrap loader security key (BSLSKEY). A 0x0AA55 at this location disables the BSL completely.
 - A zero disables the erasure of the flash if an invalid password is supplied.
- 8. The interrupt vectors at addresses 0x0FFDA to 0x0FFC0 are not used in this device and can be used for regular program code if necessary.



special function registers

Most interrupt enable bits are collected in the lowest address space. Special-function register bits not allocated to a functional purpose are not physically present in the device. This arrangement provides simple software access.

interrupt enable 1 and 2



Interrupt Enable Register 1

WDTIE Watchdog timer interrupt enable. Inactive if watchdog mode is selected.

Active if watchdog timer is configured as general-purpose timer.

OFIE Oscillator-fault-interrupt enable
NMIIE Nonmaskable-interrupt enable

ACCVIE Flash memory access violation interrupt enable

Address	7	6	5	4	3	2	1	0
01h					UCB0TXIE	UCB0RXIE	UCA0TXIE	UCA0RXIE
					rw-0	rw-0	rw-0	rw-0

Interrupt Enable Register 2

UCA0RXIE	USCI_A0 receive-interrupt enable
UCA0TXIE	USCI_A0 transmit-interrupt enable
UCB0RXIE	USCI_B0 receive-interrupt enable
UCB0TXIE	USCI_B0 transmit-interrupt enable

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

interrupt flag register 1 and 2

Address	7	6	5	4	3	2	1	0
02h				NMIIFG	RSTIFG	PORIFG	OFIFG	WDTIFG
				rw-0	rw-(0)	rw-(1)	rw-1	rw-(0)

Interrupt Flag Register 1

WDTIFG Set on watchdog timer overflow or security key violation

Reset on V_{CC} power-on or a reset condition at the RST/NMI pin in reset mode

OFIFG Flag set on oscillator fault7

PORIFG Power-on interrupt flag. Set on V_{CC} power up.

RSTIFG External reset interrupt flag. Set on a reset condition at RST/NMI pin in reset mode. Reset

on V_{CC} power up.

NMIIFG Set via RST/NMI pin

Address	7	6	5	4	3	2	1	0
03h					UCB0TX IFG	UCB0RX IFG	UCA0TX IFG	UCA0RX IFG
					rw-1	rw-0	rw-1	rw-0

Interrupt Flag Register 2

UCA0RXIFG USCI_A0 receive-interrupt flag
UCA0TXIFG USCI_A0 transmit-interrupt flag
UCB0RXIFG USCI_B0 receive-interrupt flag
UCB0TXIFG USCI_B0 transmit-interrupt flag

Legend rw: Bit can be read and written.

rw-0,1: Bit can be read and written. It is Reset or Set by PUC. rw-(0,1) Bit can be read and written. It is Reset or Set by POR.

SFR bit is not present in device.

memory organization

		MSP430F2416 MSP430F2616	MSP430F2417 MSP430F2617
Memory	Size	92KB	92KB
Main: interrupt vector	Flash	0x0FFFF - 0x0FFC0	0x0FFFF - 0x0FFC0
Main: code memory	Flash	0x18FFF - 0x02100	0x19FFF - 0x03100
RAM (total)	Size	4kB 0x020FF - 0x01100	8kB 0x030FF - 0x01100
Extended	Size	2kB 0x020FF - 0x01900	6kB 0x030FF - 0x01900
Mirrored	Size	2kB 0x018FF - 0x01100	2kB 0x018FF - 0x01100
Information memory	Size Flash	256 Byte 0x010FF - 0x01000	256 Byte 0x010FF - 0x01000
Boot memory	Size ROM	1KB 0x00FFF - 0x00C00	1KB 0x00FFF - 0x00C00
RAM (mirrored at 0x18FF to 0x01100)	Size	2KB 0x009FF - 0x00200	2KB 0x009FF - 0x00200
Peripherals	16-bit	0x001FF - 0x00100	0x001FF - 0x00100
	8-bit	0x000FF - 0x00010	0x000FF - 0x00010
	8-bit SFR	0x0000F - 0x00000	0x0000F - 0x00000

		MSP430F2618 MSP430F2418	MSP430F2619 MSP430F2419
Memory	Size	116KB	120KB
Main: interrupt vector	Flash	0x0FFFF - 0x0FFC0	0x0FFFF - 0x0FFC0
Main: code memory	Flash	0x1FFFF - 0x03100	0x1FFFF - 0x02100
RAM (total)	Size	8kB 0x030FF - 0x01100	4kB 0x020FF - 0x01100
Extended	Size	6kB 0x030FF - 0x01900	2kB 0x020FF - 0x01900
Mirrored	Size	2kB 0x018FF - 0x01100	2kB 0x018FF - 0x01100
Information memory	Size Flash	256 Byte 0x010FF - 0x01000	256 Byte 0x010FF - 0x01000
Boot memory	Size ROM	1KB 0x00FFF - 0x00C00	1KB 0x00FFF - 0x00C00
RAM (mirrored at 0x18FF to 0x01100)	Size	2KB 0x009FF - 0x00200	2KB 0x009FF - 0x00200
Peripherals	16-bit	0x001FF - 0x00100	0x001FF - 0x00100
	8-bit	0x000FF - 0x00010	0x000FF - 0x00010
	8-bit SFR	0x0000F - 0x00000	0x0000F - 0x00000

bootstrap loader (BSL)

The MSP430 BSL enables users to program the flash memory or RAM using a UART serial interface. Access to the MSP430 memory via the BSL is protected by a user-defined password. For complete description of the features of the BSL and its implementation, see the application report Features of the MSP430 Bootstrap Loader, literature number SLAA089.

BSL Function	PM, RTD Package Pins
Data Transmit	13 - P1.1
Data Receive	22 - P2.2



SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

flash memory

The flash memory can be programmed via the JTAG port, the bootstrap loader, or in-system by the CPU. The CPU can perform single-byte and single-word writes to the flash memory. Features of the flash memory include:

- Flash memory has n segments of main memory and four segments of information memory (A to D) of 64 bytes each. Each segment in main memory is 512 bytes in size.
- Segments 0 to n may be erased in one step, or each segment may be individually erased.
- Segments A to D can be erased individually, or as a group with segments 0 to n.
 Segments A to D are also called information memory.
- Segment A contains calibration data. After reset, segment A is protected against programming or erasing.
 It can be unlocked, but care should be taken not to erase this segment if the calibration data is required.
- Flash content integrity check with marginal read modes

peripherals

Peripherals are connected to the CPU through data, address, and control buses and can be handled using all instructions. For complete module descriptions, see the MSP430x2xx Family User's Guide, literature number SLAU144.

DMA controller

The DMA controller allows movement of data from one memory address to another without CPU intervention. For example, the DMA controller can be used to move data from the ADC12 conversion memory to RAM. Using the DMA controller can increase the throughput of peripheral modules. The DMA controller reduces system power consumption by allowing the CPU to remain in sleep mode without having to awaken to move data to or from a peripheral.

oscillator and system clock

The clock system in the MSP430x241x and MSP43x261x family of devices is supported by the basic clock module that includes support for a 32768-Hz watch crystal oscillator, an internal very low power, low frequency oscillator, an internal digitally-controlled oscillator (DCO) and a high frequency crystal oscillator. The basic clock module is designed to meet the requirements of both low system cost and low-power consumption. The internal DCO provides a fast turn-on clock source and stabilizes in less than 1 μ s. The basic clock module provides the following clock signals:

- Auxiliary clock (ACLK), sourced from a 32768-Hz watch crystal, a high frequency crystal, or a very low-power LF oscillator
- Main clock (MCLK), the system clock used by the CPU
- Sub-Main clock (SMCLK), the subsystem clock used by the peripheral modules

The DCO settings to calibrate the DCO output frequency are stored in the information memory segment A.



calibration data stored in information memory segment A

Calibration data is stored for the DCO and for the ADC12. It is organized in a tag-length-value (TLV) structure.

TAGS USED BY THE ADC CALIBRATION TAGS			
NAME ADDRESS VALUE DESCRIPTION			
TAG_DCO_30	0x10F6	0x01	DCO frequency calibration at VCC = 3 V and T _A = 25°C at calibration
TAG_ADC12_1	0x10DA	0x10	ADC12_1 calibration tag
TAG_EMPTY	1	0xFE	Identifier for empty memory areas

LABELS USED BY THE ADC CALIBRATION TAGS				
LABEL	CONDITION AT CALIBRATION / DESCRIPTION	SIZE	ADDRESS OFFSET	
CAL_ADC_25T85	INCHx = 0x1010; REF2_5 = 1, T _A = 85°C	word	0x000E	
CAL_ADC_25T30	INCHx = 0x1010; REF2_5 = 1, T _A = 30°C	word	0x000C	
CAL_ADC_25VREF_FACTOR	REF2_5 = 1, T _A = 30°C	word	0x000A	
CAL_ADC_15T85	INCHx = 0x1010; REF2_5 = 0, T _A = 85°C	word	0x0008	
CAL_ADC_15T30	INCHx = 0x1010; REF2_5 = 0, T _A = 30°C	word	0x0006	
CAL_ADC_15VREF_FACTOR	REF2_5 = 0, T _A = 30°C	word	0x0004	
CAL_ADC_OFFSET	External V _{REF} = 1.5 V, f _{ADC12CLK} = 5 MHz	word	0x0002	
CAL_ADC_GAIN_FACTOR	External V _{REF} = 1.5 V, f _{ADC12CLK} = 5 MHz	word	0x0000	
CAL_BC1_1MHz	+	byte	0x0007	
CAL_DCO_1MHz	+	byte	0x0006	
CAL_BC1_8MHz	-	byte	0x0005	
CAL_DCO_8MHz	-	byte	0x0004	
CAL_BC1_12MHz	-	byte	0x0003	
CAL_DCO_12MHz	-	byte	0x0002	
CAL_BC1_16MHz	-	byte	0x0001	
CAL_DCO_16MHz	-	byte	0x0000	

brownout, supply voltage supervisor (SVS)

The brownout circuit is implemented to provide the proper internal reset signal to the device during power on and power off. The SVS circuitry detects if the supply voltage drops below a user selectable level and supports both supply voltage supervision (the device is automatically reset) and supply voltage monitoring (SVM, the device is not automatically reset).

The CPU begins code execution after the brownout circuit releases the device reset. However, V_{CC} may not have ramped to $V_{CC(min)}$ at that time. The user must ensure that the default DCO settings are not changed until V_{CC} reaches $V_{CC(min)}$. If desired, the SVS circuit can be used to determine when V_{CC} reaches $V_{CC(min)}$.

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

digital I/O

There are up to eight 8-bit I/O ports implemented—ports P1 through P8:

- All individual I/O bits are independently programmable.
- Any combination of input, output, and interrupt conditions is possible.
- Edge-selectable interrupt input capability for all eight bits of ports P1 and P2.
- Read/write access to port-control registers is supported by all instructions.
- Each I/O has an individually programmable pullup/pulldown resistor.
- Ports P7/P8 can be accessed word wise.

watchdog timer+ (WDT+)

The primary function of the WDT+ module is to perform a controlled system restart after a software problem occurs. If the selected time interval expires, a system reset is generated. If the watchdog function is not needed in an application, the module can be configured as an interval timer and can generate interrupts at selected time intervals.

hardware multiplier

The multiplication operation is supported by a dedicated peripheral module. The module performs 16×16 , 16×8 , 8×16 , and 8×8 bit operations. The module is capable of supporting signed and unsigned multiplication as well as signed and unsigned multiply and accumulate operations. The result of an operation can be accessed immediately after the operands have been loaded into the peripheral registers. No additional clock cycles are required.

universal serial communication interface (USCI)

The USCI modules are used for serial data communication. The USCI module supports synchronous communication protocols such as SPI (3 pin or 4 pin) or I²C, and asynchronous combination protocols such as UART, enhanced UART with automatic baudrate detection (LIN), and IrDA.

The USCI A module provides support for SPI (3 pin or 4 pin), UART, enhanced UART, and IrDA.

The USCI B module provides support for SPI (3 pin or 4 pin) and I²C.



timer_A3

Timer_A3 is a 16-bit timer/counter with three capture/compare registers. Timer_A3 can support multiple capture/compares, PWM outputs, and interval timing. Timer_A3 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

	TIMER_A3 SIGNAL CONNECTIONS					
INPUT PIN NUMBER	DEVICE INPUT SIGNAL	MODULE INPUT NAME	MODULE BLOCK	MODULE OUTPUT SIGNAL	OUTPUT PIN NUMBER	
12 - P1.0	TACLK	TACLK				
	ACLK	ACLK] _			
	SMCLK	SMCLK	Timer	NA		
21 - P2.1	TAINCLK	INCLK				
13 - P1.1	TA0	CCI0A			13 - P1.1	
22 - P2.2	TA0	CCI0B	0000	T4.0	17 - P1.5	
	DV _{SS}	GND CCR0 TA0	27 - P2.7			
	DV _{CC}	V _{CC}				
14 - P1.2	TA1	CCI1A	1A		14 - P1.2	
	CAOUT (internal)	CCI1B	0004		18 - P1.6	
	DV _{SS}	GND	CCR1		23 - P2.3	
	DV _{CC}	V _{CC}		TA1	ADC12 (internal)	
					DAC12_0 (internal)	
					DAC12_1 (internal)	
15 - P1.3	TA2	CCI2A			15 - P1.3	
	ACLK (internal)	CCI2B	CCR2	T4.0	19 - P1.7	
	DV _{SS}	GND		CCR2	TA2	24 - P2.4
	DV _{CC}	V _{CC}				

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

timer_B7

Timer_B7 is a 16-bit timer/counter with seven capture/compare registers. Timer_B7 can support multiple capture/compares, PWM outputs, and interval timing. Timer_B7 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

	TIMER_B3/B7 SIGNAL CONNECTIONS [†]				
INPUT PIN NUMBER	DEVICE INPUT SIGNAL	MODULE INPUT NAME	MODULE BLOCK	MODULE OUTPUT SIGNAL	OUTPUT PIN NUMBER
43 - P4.7	TBCLK	TBCLK			
	ACLK	ACLK	_		
	SMCLK	SMCLK	Timer	NA	
43 - P4.7	TBCLK	INCLK			
36 - P4.0	TB0	CCI0A			36 - P4.0
36 - P4.0	TB0	CCI0B	0000	TDO	ADC12 (internal)
	DV _{SS}	GND	CCR0	TB0	
	DV _{CC}	V _{CC}			
37 - P4.1	TB1	CCI1A			37 - P4.1
37 - P4.1	TB1	CCI1B	000		ADC12 (internal)
	DV _{SS}	GND	CCR1	TB1	
	DV _{CC}	V _{CC}			
38 - P4.2	TB2	CCI2A			38 - P4.2
38 - P4.2	TB2	CCI2B	0000		DAC_0(internal)
	DV _{SS} GND CCR2 TB2	TB2	DAC_1 (internal)		
	DV _{CC}	V _{CC}			
39 - P4.3	TB3	CCI3A			39 - P4.3
39 - P4.3	TB3	CCI3B	000-		
	DV _{SS}	GND	CCR3	TB3	
	DV _{CC}	V _{CC}			
40 - P4.4	TB4	CCI4A			40 - P4.4
40 - P4.4	TB4	CCI4B			
	DV _{SS}	GND	CCR4	TB4	
	DV _{CC}	V _{CC}			
41 - P4.5	TB5	CCI5A			41 - P4.5
41 - P4.5	TB5	CCI5B	000-	TD-	
	DV _{SS}	GND	CCR5	TB5	
	DV _{CC}	V _{CC}			
42 - P4.6	TB6	CCI6A			42 - P4.6
	ACLK (internal)	CCI6B	0075	T	
	DV _{SS}	GND	CCR6	TB6	
	DV _{CC}	V _{CC}			



SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

comparator_A+

The primary function of the comparator_A+ module is to support precision slope analog-to-digital conversions, battery-voltage supervision, and monitoring of external analog signals.

ADC₁₂

The ADC12 module supports fast, 12-bit analog-to-digital conversions. The module implements a 12-bit SAR core, sample select control, reference generator, and a 16-word conversion-and-control buffer. The conversion-and-control buffer allows up to 16 independent ADC samples to be converted and stored without any CPU intervention.

DAC₁₂

The DAC12 module is a 12-bit, R-ladder, voltage output DAC. The DAC12 may be used in 8-bit or 12-bit mode and may be used in conjunction with the DMA controller. When multiple DAC12 modules are present, they may be grouped together for synchronous operation.

peripheral file map

	PERIPHERAL FILE MAP		
DMA [†]	DMA channel 2 transfer size	DMA2SZ	0x01F2
	DMA channel 2 destination address	DMA2DA	0x01EE
	DMA channel 2 source address	DMA2SA	0x01EA
	DMA channel 2 control	DMA2CTL	0x01E8
	DMA channel 1 transfer size	DMA1SZ	0x01E6
	DMA channel 1 destination address	DMA1DA	0x01E2
	DMA channel 1 source address	DMA1SA	0x01DE
	DMA channel 1 control	DMA1CTL	0x01DC
	DMA channel 0 transfer size	DMA0SZ	0x01DA
	DMA channel 0 destination address	DMA0DA	0x01D6
	DMA channel 0 source address	DMA0SA	0x01D2
	DMA channel 0 control	DMA0CTL	0x01D0
	DMA module interrupt vector word	DMAIV	0x0126
	DMA module control 1	DMACTL1	0x0124
	DMA module control 0	DMACTL0	0x0122
DAC12 [†]	DAC12_1 data	DAC12_1DAT	0x01CA
	DAC12_1 control	DAC12_1CTL	0x01C2
	DAC12_0 data	DAC12_0DAT	0x01C8
	DAC12_0 control	DAC12_0CTL	0x01C0
ADC12	Interrupt-vector-word register	ADC12IV	0x01A8
	Inerrupt-enable register	ADC12IE	0x01A6
	Inerrupt-flag register	ADC12IFG	0x01A4
	Control register 1	ADC12CTL1	0x01A2
	Control register 0	ADC12CTL0	0x01A0
	Conversion memory 15	ADC12MEM15	0x015E
	Conversion memory 14	ADC12MEM14	0x015C
	Conversion memory 13	ADC12MEM13	0x015A
	Conversion memory 12	ADC12MEM12	0x0158
	Conversion memory 11	ADC12MEM11	0x0156
	Conversion memory 10	ADC12MEM10	0x0154
	Conversion memory 9	ADC12MEM9	0x0152
	Conversion memory 8	ADC12MEM8	0x0150
	Conversion memory 7	ADC12MEM7	0x014E
	Conversion memory 6	ADC12MEM6	0x014C
	Conversion memory 5	ADC12MEM5	0x014A
	Conversion memory 4	ADC12MEM4	0x0148
	Conversion memory 3	ADC12MEM3	0x0146
	Conversion memory 2	ADC12MEM2	0x0144
	Conversion memory 1	ADC12MEM1	0x0142
	Conversion memory 0	ADC12MEM0	0x0140

[†] MSP430F261x devices only



	PERIPHERAL FILE MAP (CONTINUED)		
ADC12	ADC memory-control register15	ADC12MCTL15	0x008F
(continued)	ADC memory-control register14	ADC12MCTL14	0x008E
	ADC memory-control register13	ADC12MCTL13	0x008D
	ADC memory-control register12	ADC12MCTL12	0x008C
	ADC memory-control register11	ADC12MCTL11	0x008B
	ADC memory-control register10	ADC12MCTL10	0x008A
	ADC memory-control register9	ADC12MCTL9	0x0089
	ADC memory-control register8	ADC12MCTL8	0x0088
	ADC memory-control register7	ADC12MCTL7	0x0087
	ADC memory-control register6	ADC12MCTL6	0x0086
	ADC memory-control register5	ADC12MCTL5	0x0085
	ADC memory-control register4	ADC12MCTL4	0x0084
	ADC memory-control register3	ADC12MCTL3	0x0083
	ADC memory-control register2	ADC12MCTL2	0x0082
	ADC memory-control register1	ADC12MCTL1	0x0081
	ADC memory-control register0	ADC12MCTL0	0x0080
Timer_B7	Capture/compare register 6	TBCCR6	0x019E
	Capture/compare register 5	TBCCR5	0x019C
	Capture/compare register 4	TBCCR4	0x019A
	Capture/compare register 3	TBCCR3	0x0198
	Capture/compare register 2	TBCCR2	0x0196
	Capture/compare register 1	TBCCR1	0x0194
	Capture/compare register 0	TBCCR0	0x0192
	Timer_B register	TBR	0x0190
	Capture/compare control 6	TBCCTL6	0x018E
	Capture/compare control 5	TBCCTL5	0x018C
	Capture/compare control 4	TBCCTL4	0x018A
	Capture/compare control 3	TBCCTL3	0x0188
	Capture/compare control 2	TBCCTL2	0x0186
	Capture/compare control 1	TBCCTL1	0x0184
	Capture/compare control 0	TBCCTL0	0x0182
	Timer_B control	TBCTL	0x0180
	Timer_B interrupt vector	TBIV	0x011E
Timer_A3	Capture/compare register 2	TACCR2	0x0176
	Capture/compare register 1	TACCR1	0x0174
	Capture/compare register 0	TACCR0	0x0172
	Timer_A register	TAR	0x0170
	Reserved		0x016E
	Reserved		0x016C
	Reserved		0x016A
	Reserved		0x0168
	Capture/compare control 2	TACCTL2	0x0166
	Capture/compare control 1	TACCTL1	0x0164
	Capture/compare control 0	TACCTL0	0x0162
	Timer_A control	TACTL	0x0160
	Timer_A interrupt vector	TAIV	0x012E



	PERIPHERAL FILE MAP (CONTINU	IED)	_
Hardware	Sum extend	SUMEXT	0x013E
Multiplier	Result high word	RESHI	0x013C
	Result low word	RESLO	0x013A
	Second operand	OP2	0x0138
	Multiply signed +accumulate/operand1	MACS	0x0136
	Multiply+accumulate/operand1	MAC	0x0134
	Multiply signed/operand1	MPYS	0x0132
	Multiply unsigned/operand1	MPY	0x0130
Flash	Flash control 4	FCTL4	0x01BE
	Flash control 3	FCTL3	0x012C
	Flash control 2	FCTL2	0x012A
	Flash control 1	FCTL1	0x0128
Watchdog	Watchdog Timer control	WDTCTL	0x0120
USCI A0/B0	USCI A0 auto baud rate control	UCA0ABCTL	0x005D
	USCI A0 transmit buffer	UCA0TXBUF	0x0067
	USCI A0 receive buffer	UCA0RXBUF	0x0066
	USCI A0 status	UCA0STAT	0x0065
	USCI A0 modulation control	UCA0MCTL	0x0064
	USCI A0 baud rate control 1	UCA0BR1	0x0063
	USCI A0 baud rate control 0	UCA0BR0	0x0062
	USCI A0 control 1	UCA0CTL1	0x0061
	USCI A0 control 0	UCA0CTL0	0x0060
	USCI A0 IrDA receive control	UCA0IRRCTL	0x005F
	USCI A0 IrDA transmit control	UCA0IRTCLT	0x005E
	USCI B0 transmit buffer	UCB0TXBUF	0x006F
	USCI B0 receive buffer	UCB0RXBUF	0x006E
	USCI B0 status	UCB0STAT	0x006D
	USCI B0 I2C Interrupt enable	UCB0CIE	0x006C
	USCI B0 baud rate control 1	UCB0BR1	0x006B
	USCI B0 baud rate control 0	UCB0BR0	0x006A
	USCI B0 control 1	UCB0CTL1	0x0069
	USCI B0 control 0	UCB0CTL0	0x0068
	USCI B0 I2C slave address	UCB0SA	0x011A
	USCI B0 I2C own address	UCB0OA	0x0118
USCI A1/B1	USCI A1 auto baud rate control	UCA1ABCTL	0x00CD
	USCI A1 transmit buffer	UCA1TXBUF	0x00D7
	USCI A1 receive buffer	UCA1RXBUF	0x00D6
	USCI A1 status	UCA1STAT	0x00D5
	USCI A1 modulation control	UCA1MCTL	0x00D4
	USCI A1 baud rate control 1	UCA1BR1	0x00D3
	USCI A1 baud rate control 0	UCA1BR0	0x00D2
	USCI A1 control 1	UCA1CTL1	0x00D1
	USCI A1 control 0	UCA1CTL0	0x00D0
	USCI A1 IrDA receive control	UCA1IRRCTL	0x00CF
	USCI A1 IrDA transmit control	UCA1IRTCLT	0x00CE



	PERIPHERAL FILE MAP (CONTINUED)		
USCI A1/B1	USCI B1 transmit buffer	UCB1TXBUF	0x00DF
(continued)	USCI B1 receive buffer	UCB1RXBUF	0x00DE
	USCI B1 status	UCB1STAT	0x00DD
	USCI B1 I2C Interrupt enable	UCB1CIE	0x00DC
	USCI B1 baud rate control 1	UCB1BR1	0x00DB
	USCI B1 baud rate control 0	UCB1BR0	0x00DA
	USCI B1 control 1	UCB1CTL1	0x00D9
	USCI B1 control 0	UCB1CTL0	0x00D8
	USCI B1 I2C slave address	UCB1SA	0x017E
	USCI B1 I2C own address	UCB1OA	0x017C
	USCI A1/B1 interrupt enable	UC1IE	0x0006
	USCI A1/B1 interrupt flag	UC1IFG	0x0007
Comparator_A+	Comparator_A port disable	CAPD	0x005B
	Comparator_A control2	CACTL2	0x005A
	Comparator A control1	CACTL1	0x0059
Basic Clock	Basic clock system control3	BCSCTL3	0x0053
	Basic clock system control2	BCSCTL2	0x0058
	Basic clock system control1	BCSCTL1	0x0057
	DCO clock frequency control	DCOCTL	0x0056
Brownout, SVS	SVS control register (reset by brownout signal)	SVSCTL	0x0055
Port PA [†]	Port PA resistor enable	PAREN	0x0014
	Port PA selection	PASEL	0x003E
	Port PA direction	PADIR	0x003C
	Port PA output	PAOUT	0x003A
	Port PA input	PAIN	0x0038
Port P8 [†]	Port P8 resistor enable	P8REN	0x0015
	Port P8 selection	P8SEL	0x003F
	Port P8 direction	P8DIR	0x003D
	Port P8 output	P8OUT	0x003B
	Port P8 input	P8IN	0x0039
Port P7 [†]	Port P7 resistor enable	P7REN	0x0014
	Port P7 selection	P7SEL	0x003E
	Port P7 direction	P7DIR	0x003C
	Port P7 output	P7OUT	0x003A
	Port P7 input	P7IN	0x0038
Port P6	Port P6 resistor enable	P6REN	0x0013
	Port P6 selection	P6SEL	0x0037
	Port P6 direction	P6DIR	0x0036
	Port P6 output	P6OUT	0x0035
	Port P6 input	P6IN	0x0034
Port P5	Port P5 resistor enable	P5REN	0x0012
.	Port P5 selection	P5SEL	0x0033
	Port P5 direction	P5DIR	0x0033
	Port P5 output	P5OUT	0x0032
	Port P5 output	P5IN	0x0031

^{† 80-}pin devices only



	PERIPHERAL FILE MAP (CONT	INUED)	
Port P4	Port P4 selection	P4SEL	0x001F
	Port P4 resistor enable	P4REN	0x0011
	Port P4 direction	P4DIR	0x001E
	Port P4 output	P4OUT	0x001D
	Port P4 input	P4IN	0x001C
Port P3	Port P3 resistor enable	P3REN	0x0010
	Port P3 selection	P3SEL	0x001B
	Port P3 direction	P3DIR	0x001A
	Port P3 output	P3OUT	0x0019
	Port P3 input	P3IN	0x0018
Port P2	Port P2 resistor enable	P2REN	0x002F
	Port P2 selection	P2SEL	0x002E
	Port P2 interrupt enable	P2IE	0x002D
	Port P2 interrupt-edge select	P2IES	0x002C
	Port P2 interrupt flag	P2IFG	0x002B
	Port P2 direction	P2DIR	0x002A
	Port P2 output	P2OUT	0x0029
	Port P2 input	P2IN	0x0028
Port P1	Port P1 resistor enable	P1REN	0x0027
	Port P1 selection	P1SEL	0x0026
	Port P1 interrupt enable	P1IE	0x0025
	Port P1 interrupt-edge select	P1IES	0x0024
	Port P1 interrupt flag	P1IFG	0x0023
	Port P1 direction	P1DIR	0x0022
	Port P1 output	P1OUT	0x0021
	Port P1 input	P1IN	0x0020
Special Functions	SFR interrupt flag2	IFG2	0x0003
	SFR interrupt flag1	IFG1	0x0002
	SFR interrupt enable2	IE2	0x0001
	SFR interrupt enable1	IE1	0x0000



absolute maximum ratings (see Note 1)

Voltage applied at V_{CC} to V_{SS}	0.3 V to 4.1 V
Voltage applied to any pin (see Note	2) -0.3 V to V _{CC} + 0.3 V
Diode current at any device terminal	
Storage temperature: Unprogramme	ed device (see Note 3)
Programmed of	device (see Note 3)40°C to 105°C

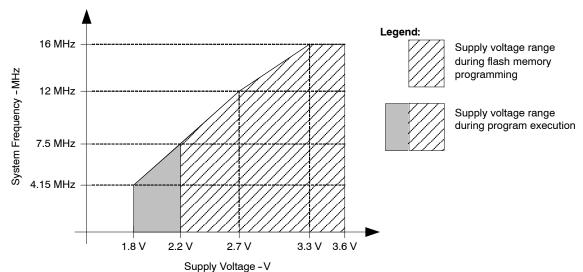
NOTES: 1. Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- 2. All voltages referenced to V_{SS}. The JTAG fuse-blow voltage, V_{FB}, is allowed to exceed the absolute maximum rating. The voltage is applied to the TDI/TCLK pin when blowing the JTAG fuse.
- 3. Higher temperature may be applied during board soldering process according to the current JEDEC J-STD-020 specification, with peak reflow temperatures not higher than classified on the device label on the shipping boxes or reels.

recommended operating conditions

PARAMETER	MIN	MAX	UNIT	
Supply voltage during program execution, V _{CC}	AV _{CC} = DV _{CC} = V _{CC} (see Note 1)	1.8	3.6	V
Supply voltage during flash memory programming, V _{CC}	AV _{CC} = DV _{CC} = V _{CC} (see Note 1)	2.2	3.6	V
Supply voltage, V _{SS}	$AV_{SS} = DV_{SS} = V_{SS}$	0.0	0.0	V
Operating free-air temperature, T _A	I version	-40		20
	T version	-40	105	°C
	V _{CC} = 1.8 V, Duty cycle = 50% ± 10%	dc	4.15	
Processor frequency f _{SYSYTEM} (maximum MCLK frequency) (see Notes 2 and 3 and Figure 1)	V _{CC} = 2.7 V, Duty cycle = 50% ± 10%	dc	12	MHz
	V _{CC} ≥ 3.3 V, Duty cycle = 50% ± 10%	dc	16	

- NOTES: 1. It is recommended to power AV_{CC} and DV_{CC} from the same source. A maximum difference of 0.3 V between AV_{CC} and DV_{CC} can be tolerated during power-up.
 - The MSP430 CPU is clocked directly with MCLK.Both the high and low phase of MCLK must not exceed the pulse width of the specified maximum frequency.
 - 3. Modules might have a different maximum input clock specification. See the specification of the respective module in this data sheet.



NOTE: Minimum processor frequency is defined by system clock. Flash program or erase operations require a minimum V_{CC} of 2.2 V.

Figure 1. Operating Area



SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

active mode supply current into V_{CC} excluding external current (see Notes 1 and 2)

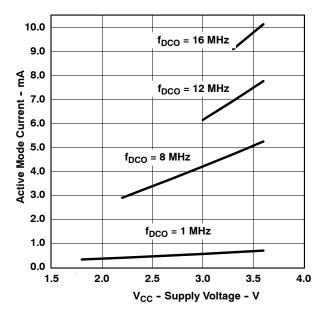
PA	RAMETER	TEST CONDITIONS	T _A	VCC	MIN	TYP	MAX	UNIT
		f _{DCO} = f _{MCLK} = f _{SMCLK} = 1 MHz, f _{ACLK} = 32,768 Hz,	-40°C to 85°C	2.2 V		365	395	
	Active mode (AM)	Program executes from flash, BCSCTL1 = CALBC1 1MHZ,	105°C	2.2 V		375	420	uΑ
IAM, 1MHz	current (1 MHz)	DCOCTL = CALDCO_1MHZ,	-40°C to 85°C	3 V		515	560	μΑ
		CPUOFF = 0, SCG0 = 0, SCG1 = 0, OSCOFF = 0	105°C	3 V		525	595	
		f _{DCO} = f _{MCLK} = f _{SMCLK} = 1 MHz,	-40°C to 85°C	2.2 V		330	370	
	Active mode (AM)	f _{ACLK} = 32,768 Hz, Program executes in RAM, BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, CPUOFF = 0, SCG0 = 0, SCG1 = 0, OSCOFF = 0	105°C	2.2 V		340	390	uΑ
I I A A A A A A A I I	current (1 MHz)		-40°C to 85°C	0.1/		460	495	μΑ
			105°C	3 V		470	520	
	$f_{MCLK} = f_{SMCLK} = f_{ACLK} = 32,768 \text{ Hz/8} = 4,096 \text{ Hz},$	-40°C to 85°C	2.2 V		2.1	9		
	Active mode (AM)	f _{DCO} = 0 Hz, Program executes in flash,	105°C	2.2 V		15	31	μA
I _{AM, 4kHz}	current (4 kHz)	SELMx = 11, SELS = 1, DIVMx = DIVSx = DIVAx = 11,	-40°C to 85°C	3 V		3	11	μΑ
		CPUOFF = 0, SCG0 = 1, SCG1 = 0, OSCOFF = 0	105°C	3 V		19	32	
		$f_{MCLK} = f_{SMCLK} = f_{DCO(0, 0)} \approx 100 \text{ kHz},$	-40°C to 85°C	2.2 V		67	86	
	Active mode (AM) current (100 kHz) Active mode (AM) current (100 kHz) Active mode (AM) CURRENT OF HZ, Program executes in flash, RSELx = 0, DCOx = 0, CPUOFF = 0, SCG0 = 0, SCG1 = 0,		105°C	2.2 V		80	99	4
I _{AM,100kHz}		current (100 kHz) RSELx = 0, DCOx = 0,	-40°C to 85°C	3 V		84	107	μΑ
		OSCOFF = 1	105°C	3 V		99	128	

NOTES: 1. All inputs are tied to 0 V or V_{CC} . Outputs do not source or sink any current.

^{2.} The currents are characterized with a micro crystal CC4V-T1A SMD crystal with a load capacitance of 9 pF. The internal and external load capacitance is chosen to closely match the required 9 pF.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

typical characteristics - active mode supply current (into DV_{CC} + AV_{CC})



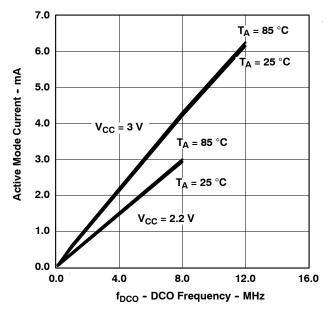


Figure 2. Active Mode Current vs V_{CC} , $T_A = 25$ °C

Figure 3. Active Mode Current vs DCO Frequency

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

low-power mode supply current into V_{CC} excluding external current (see Notes 1 and 2)

PARAMETER		TEST CONDITIONS	T _A	VCC	MIN	TYP	MAX	UNIT
		f _{MCLK} = 0 MHz,	-40°C to 85°C			68	83	
	Low-power mode 0	f _{SMCLK} = f _{DCO} = 1 MHz, f _{ACLK} = 32,768 Hz,	105°C	2.2 V		83	98	μA
ILPM0, 1MHz	(LPM0) current, see Note 3	BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ,	-40°C to 85°C	234		87	105	μΑ
		CPUOFF = 1, SCG0 = 0, SCG1 = 0, OSCOFF = 0	105°C	3 V		100	125	
		f _{MCLK} = 0MHz,	-40°C to 85°C	0.01/		37	49	
I _{LPM0} ,	Low-power mode 0	$f_{SMCLK} = f_{DCO(0, 0)} \approx 100 \text{ kHz},$ $f_{ACLK} = 0 \text{ Hz},$	105°C	2.2 V		50	62	
100kHz	(LPM0) current, see Note 3	RSELx = 0, $DCOx = 0$,	-40°C to 85°C			40	55	μΑ
		CPUOFF = 1, SCG0 = 0, SCG1 = 0, OSCOFF = 1	105°C	3 V		57	73	
		f _{MCLK} = f _{SMCLK} = 0 MHz, f _{DCO} = 1 MHz,	-40°C to 85°C	2.2 V		23	33	
	Low-power mode 2	f _{ACLK} = 32,768 Hz, BCSCTL1 = CALBC1_1MHZ,	105°C	2.2 V		35	46	μΑ
I _{LPM2}	(LPM2) current, see Note 4	DCOCTL = CALDCO_1MHZ, CPUOFF = 1, SCG0 = 0, SCG1 = 1,	-40°C to 85°C	3 V		25	36	μΑ
		OSCOFF = 0	105°C	3 V		40	55	
		de 3 f _{DCO} = f _{MCLK} = f _{SMCLK} = 0 MHz,	-40°C			8.0	1.2	- - μΑ
			25°C	2.2 V		1	1.3	
			85°C	2.2 V		4.6	7	
1	Low-power mode 3 (LPM3) current,		105°C			14	24	
I _{LPM3,LFXT1}	see Note 4	CPUOFF = 1, SCG0 = 1, SCG1 = 1,	-40°C			0.9	1.3	μΑ
		OSCOFF = 0	25°C	3 V		1.1	1.5	
			85°C	5 V		5.5	8	
			105°C			17	30	
			-40°C			0.4	1.0	
			25°C	2.2 V		0.5	1.0	
		f _{DCO} = f _{MCLK} = f _{SMCLK} = 0 MHz,	85°C	2.2 V		4.3	6.5	μΑ
1	Low-power mode 3	fachk from internal LF oscillator (VLO),	105°C			14	24	
I _{LPM3,VLO}	(LPM3) current,	CPUOFF = 1, SCG0 = 1, SCG1 = 1,	-40°C			0.6	1.2	
	see Note 4	OSCOFF = 0	25°C	3 V		0.6	1.2	
			85°C	υν		5	7.5	
			105°C			16.5	29.5	

NOTES: 1. All inputs are tied to 0 V or V_{CC} . Outputs do not source or sink any current.

- 3. Current for Brownout and WDT+ is included. The WDT+ is clocked by SMCLK.
- 4. Current for Brownout and WDT+ is included. The WDT+ is clocked by ACLK.



^{2.} The currents are characterized with a micro crystal CC4V-T1A SMD crystal with a load capacitance of 9 pF. The internal and external load capacitance is chosen to closely match the required 9 pF.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

low-power mode supply current into V_{CC} excluding external current (see Notes 1 and 2) (continued)

	PARAMETER	TEST CONDITIONS	T _A	VCC	MIN	TYP	MAX	UNIT
Low-power mode (LPM4) current,	I ow-nower mode 4	fDCO = fMCLK = fSMCLK = 0 MHz,	-40°C			0.1	0.5	
	•	DOG MIGER SMOER	25°C			0.1	0.5	
ILPM4	see Note 3 CPUOFF = 1, SCG0 = 1, SCG1 = 1,	85°C	2.2 V		4	6	μΑ	
		OSCOFF = 1	105°C			13	23	
	Low-nower mode 4	Note 3 CPUOFF = 1, SCG0 = 1, SCG1 = 1,	-40°C			0.2	0.5	
1.	(LPM4) current, $f_{ACLK} = 0 \text{ Hz}$,		25°C	21/		0.2	0.5	
I _{LPM4}	see Note 3		85°C	3 V		4.7	7	μΑ
		OSCOFF = 1	105°C			14	24	

NOTES: 1. All inputs are tied to 0 V or V_{CC}. Outputs do not source or sink any current.

- 2. The currents are characterized with a micro crystal CC4V-T1A SMD crystal with a load capacitance of 9 pf. The internal and external load capacitance is chosen to closely match the required 9 pf.
- 3. Current for Brownout included.

typical characteristics - LPM4 current

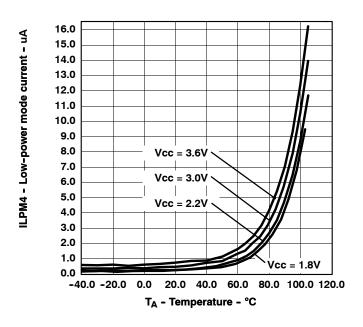


Figure 4. I_{LPM4} - LPM4 Current vs Temperature

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

Schmitt-trigger inputs - ports P1 through P8, RST/NMI, JTAG, XIN, and XT2IN (see Note 4)

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP MAX	UNIT
	Positive-going input threshold voltage			0.45 V _{CC}	0.75 V _C	;
V _{IT+} Po			2.2 V	1.0	1.6	5 V
			3 V	1.35	2.2	5
V _{IT-}	Negative-going input threshold voltage			0.25 V _{CC}	0.55 V _C	;
			2.2 V	0.55	1.3	2 V
			3 V	0.75	1.6	5
V	Input voltage bystoreeig (/ V)		2.2 V	0.2	1.) /
V_{hys}	Input voltage hysteresis (V _{IT+} - V _{IT-})		3 V	0.3	1.9	
R _{Pull}	Pullup/pulldown resistor	Pullup: V _{IN} = V _{SS} , Pulldown: V _{IN} = V _{CC}		20	35 5	kΩ
CI	Input capacitance	$V_{IN} = V_{SS}$ or V_{CC}			5	pF

NOTE 4: XIN and XT2IN in bypass mode only.

inputs - ports P1 and P2

PARAMETER TEST CONDITIONS		VCC	MIN	MAX	UNIT	
t _{int}	External interrupt timing	Port P1, P2: P1.x to P2.x, external trigger pulse width to set the interrupt flag (see Note)	2.2 V/3 V	20		ns

NOTE: The external signal sets the interrupt flag every time the minimum $t_{(int)}$ parameters are met. It may be set even with trigger signals shorter than $t_{(int)}$.

leakage current - ports P1 through P8 (see Note 1 and 2)

PARAMETER		TEST CONDITIONS	VCC	MIN MAX	UNIT
I _{lkg (Px.x)}	High-impedance leakage current	see Notes 1 and 2	2.2 V/3 V	±50	nA

NOTES: 1. The leakage current is measured with VSS or VCC applied to the corresponding pin(s), unless otherwise noted.

2. The leakage of digital port pins is measured individually. The port pin is selected for input and the pull-up/pull-down resistor is disabled..

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

standard inputs - RST/NMI

	PARAMETER	TEST CONDITIONS	VCC	MIN	MAX	UNIT
V_{IL}	Low-level input voltage		2.2 V/3 V	V_{SS}	V _{SS} +0.6	٧
V_{IH}	High-level input voltage		2.2 V/3 V	0.8×V _{CC}	V_{CC}	V

outputs - ports P1 through P8

	PARAMETER	TEST CONDITIONS	VCC	MIN	MAX	UNIT
		I _{OH(max)} = -1.5 mA (see Note 2)	2.2 V	V _{CC} -0.25	V_{CC}	
V _{OH} High-level output voltage	I _{OH(max)} = -6 mA (see Note 2)	2.2 V	V _{CC} -0.6	V_{CC}	v	
	I _{OH(max)} = -1.5 mA (see Note 2)	0.1/	V _{CC} -0.25	V_{CC}	V	
		I _{OH(max)} = -6 mA (see Note 2)	3 V	V _{CC} -0.6	V_{CC}	
		I _{OL(max)} = 1.5 mA (see Note 2)	001/	V_{SS}	V _{SS} +0.25	
\ <u>,</u>	Low level output voltage	I _{OL(max)} = 6 mA (see Note 2)	2.2 V	V_{SS}	V _{SS} +0.6	V
V _{OL}		I _{OL(max)} = 1.5 mA (see Note 2)	3 V	V_{SS}	V _{SS} +0.25	V
		I _{OL(max)} = 6 mA (see Note 2)	3 V	V_{SS}	V _{SS} +0.6	

NOTES: 1. The maximum total current, I_{OH(max)} and I_{OL(max)}, for all outputs combined, should not exceed ±12 mA to satisfy the maximum voltage drop specified.

2. The maximum total current, I_{OH(max)} and I_{OL(max)}, for all outputs combined, should not exceed ±48 mA to satisfy the maximum voltage drop specified.

output frequency - ports P1 through P8

	PARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	UNIT
,	Port output frequency	P1.4/SMCLK, C_L = 20 pF, R_L = 1 k Ω	2.2 V	DC		10	
f _{Px.y}	with load	(see Notes 1 and 2)	3.0 V	DC		12	MHz
	Olaska arterit francisca	P2.0/ACLK/CA2, P1.4/SMCLK, C _L = 20 pF	2.2 V	DC		12	NAL 1-
†Port_CLK	CLK Clock output frequency	(see Note 2)	3.3 V	DC		16	MHz
		P5.6/ACLK, C _L = 20 pF, LF mode		30	50	70	
		P5.6/ACLK, C _L = 20 pF, XT1 mode		40	50	60	%
	Duty cycle of output	P5.4/MCLK, C _L = 20 pF, XT1 mode		40		60	
t _(Xdc)	frequency	P5.4/MCLK, C _L = 20 pF, DCO		50% - 15 ns	50%	50% + 15 ns	
		P1.4/SMCLK, C _L = 20 pF, XT2 mode		40		60	%
		P1.4/SMCLK, C _L = 20 pF, DCO		50% - 15 ns		50% + 15 ns	

NOTES: 1. A resistive divider with 2 times 0.5 k Ω between V_{CC} and V_{SS} is used as load. The output is connected to the center tap of the divider.

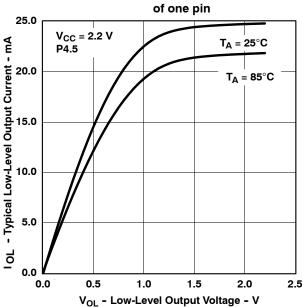
2. The output voltage reaches at least 10% and 90% V_{CC} at the specified toggle frequency.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

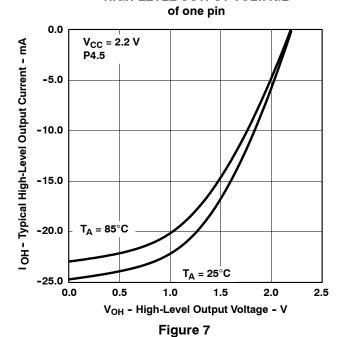
typical characteristics - outputs



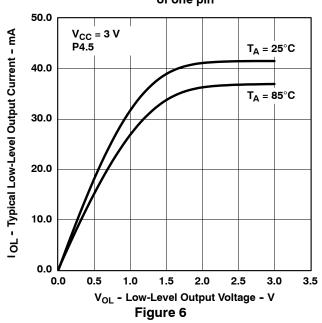


TYPICAL HIGH-LEVEL OUTPUT CURRENT vs
HIGH-LEVEL OUTPUT VOLTAGE

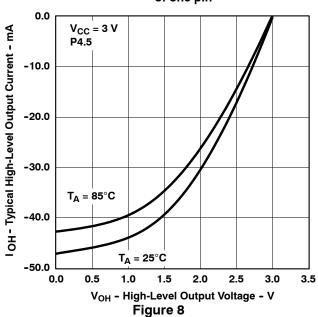
Figure 5



TYPICAL LOW-LEVEL OUTPUT CURRENT vs LOW-LEVEL OUTPUT VOLTAGE of one pin



TYPICAL HIGH-LEVEL OUTPUT CURRENT vs HIGH-LEVEL OUTPUT VOLTAGE of one pin



POR/brownout reset (BOR) (see Notes 1 and 2)

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
V _{CC(start)}	operating voltage	$\mathrm{dV_{CC}/dt} \leq$ 3 V/s			0.7 × \	/ _(B_IT-)	V
V _(B_IT-)	negative going V _{CC} reset threshold voltage	$\mathrm{dV_{CC}/dt} \leq$ 3 V/s				1.71	V
V _{hys(B_IT-)}	V _{CC} reset threshold hysteresis	$\mathrm{dV_{CC}/dt} \leq$ 3 V/s		70	130	210	mV
t _{d(BOR)}	BOR reset release delay time					2000	μs
t _{reset}	Pulse length at RST/NMI pin to accept a reset		2.2 V / 3 V	2			μS

- NOTES: 1. The current consumption of the brownout module is included in the I_{CC} current consumption data. The voltage level $V_{(B_IT-)} + V_{hys(B_IT-)}$ is $\leq 1.8 \text{ V}$.
 - During power up, the CPU begins code execution following a period of t_{d(BOR)} after V_{CC} = V_(B_IT-) + V_{hys(B_IT-)}. The default DCO settings must not be changed until V_{CC} ≥ V_{CC(MIN)}, where V_{CC(min)} is the minimum supply voltage for the desired operating frequency.

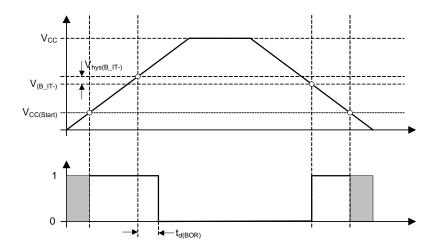


Figure 9. POR/Brownout Reset (BOR) vs Supply Voltage

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

typical characteristics - POR/brownout reset (BOR)

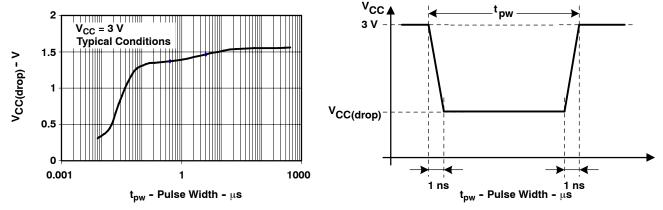


Figure 10. V_{CC(drop)} Level With a Square Voltage Drop to Generate a POR/Brownout Signal

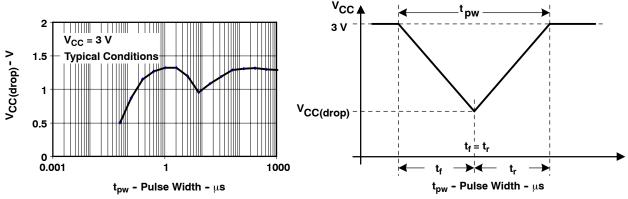


Figure 11. V_{CC(drop)} Level With a Triangle Voltage Drop to Generate a POR/Brownout Signal

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

SVS (supply voltage supervisor/monitor)

PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
	dV _{CC} /dt > 30 V/ms (see Figure 12)		5		150	
t(SVSR)	dV _{CC} /dt ≤ 30 V/ms				2000	μs
t _{d(SVSon)}	SVSON, switch from VLD = 0 to VLD ≠ 0, V _{CC} = 3 V		20		150	μs
t _{settle}	VLD ≠ 0 [‡]				12	μS
V _(SVSstart)	VLD ≠ 0, V _{CC} /dt ≤ 3 V/s (see Figure 12)			1.55	1.7	V
,		VLD = 1	70	120	210	mV
V _{hvs(SVS IT-)}	V _{CC} /dt ≤ 3 V/s (see Figure 12)	VLD = 2 to 14	V _(SVS_IT-) × 0.004		V _(SVS_IT-) × 0.016	٧
·,-(- · - <u>-</u> .· · ,	$V_{CC}/dt \le 3 \text{ V/s}$ (see Figure 12), External voltage applied on A7	VLD = 15	4.4		20	mV
		VLD = 1	1.8	1.9	2.05	
		VLD = 2	1.94	2.1	2.25	
		VLD = 3	2.05	2.2	2.37	
		VLD = 4	2.14	2.3	2.48	
		VLD = 5	2.24	2.4	2.6	
		VLD = 6	2.33	2.5	2.71	
	V _{CC} /dt ≤ 3 V/s (see Figure 12 and Figure 13)	VLD = 7	2.46	2.65	2.86	
V _{hys(SVS_IT-)} V _{CC} /dt ≤ 3 \ on A7	VCC/dt ≤ 3 V/s (see i igule 12 and i igule 13)	VLD = 8	2.58	2.8	3	V
v (SVS_II-)		VLD = 9	2.69	2.9	12 1.7 210 V(SVS_IT-) × 0.016 20 2.05 2.25 2.37 2.48 2.6 2.71 2.86	· •
		VLD = 10	2.83	3.05	3.29	
		VLD = 11	2.94	3.2	3.42	
		VLD = 12	3.11	3.35	3.61 [†]	
		VLD = 13	3.24	3.5	3.76 [†]	
		VLD = 14	3.43	3.7†	3.99†	
	V _{CC} /dt ≤ 3 V/s (see Figure 12 and Figure 13), External voltage applied on A7	VLD = 15	1.1	1.2	1.3	
I _{CC(SVS)} (see Note 1)	VLD ≠ 0, V _{CC} = 2.2 V/3 V			10	15	μΑ

 $^{^{\}dagger}$ The recommended operating voltage range is limited to 3.6 V.

NOTE 1: The current consumption of the SVS module is not included in the I_{CC} current consumption data.



[‡] t_{settle} is the settling time that the comparator o/p needs to have a stable level after VLD is switched VLD ≠ 0 to a different VLD value somewhere between 2 and 15. The overdrive is assumed to be > 50 mV.

typical characteristics

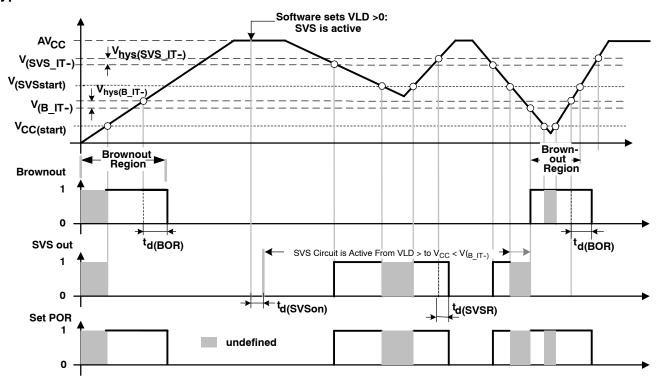


Figure 12. SVS Reset (SVSR) vs Supply Voltage

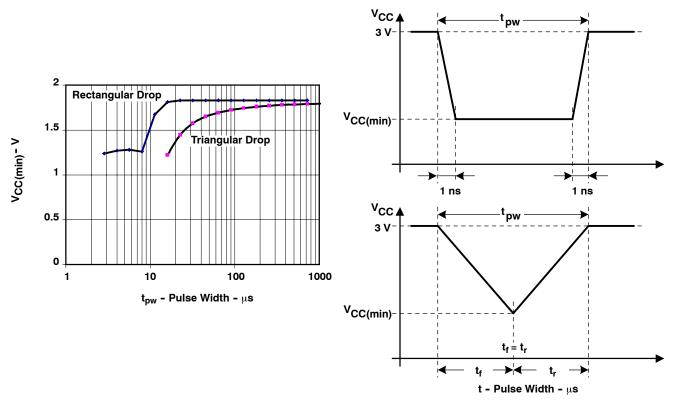


Figure 13. V_{CC(min)}: Square Voltage Drop and Triangle Voltage Drop to Generate an SVS Signal (VLD = 1)



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

main DCO characteristics

- All ranges selected by RSELx overlap with RSELx + 1: RSELx = 0 overlaps RSELx = 1, ... RSELx = 14 overlaps RSELx = 15.
- DCO control bits DCOx have a step size as defined by parameter S_{DCO}.
- Modulation control bits MODx select how often f_{DCO(RSEL,DCO+1)} is used within the period of 32 DCOCLK cycles. The frequency f_{DCO(RSEL,DCO)} is used for the remaining cycles. The frequency is an average equal to:

$$f_{average} = \frac{32 \times f_{DCO(RSEL,DCO)} \times f_{DCO(RSEL,DCO+1)}}{MOD \times f_{DCO(RSEL,DCO)} + (32 - MOD) \times f_{DCO(RSEL,DCO+1)}}$$

DCO frequency

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
		RSELx < 14		1.8		3.6	
Vcc	Supply voltage range	RSELx = 14		2.2		3.6	٧
		RSELx = 15	1	3.0		3.6	
f _{DCO(0,0)}	DCO frequency (0, 0)	RSELx = 0, $DCOx = 0$, $MODx = 0$	2.2 V/3 V	0.06		0.14	MHz
f _{DCO(0,3)}	DCO frequency (0, 3)	RSELx = 0, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.07		0.17	MHz
f _{DCO(1,3)}	DCO frequency (1, 3)	RSELx = 1, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.10		0.20	MHz
f _{DCO(2,3)}	DCO frequency (2, 3)	RSELx = 2, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.14		0.28	MHz
f _{DCO(3,3)}	DCO frequency (3, 3)	RSELx = 3, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.20		0.40	MHz
f _{DCO(4,3)}	DCO frequency (4, 3)	RSELx = 4, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.28		0.54	MHz
f _{DCO(5,3)}	DCO frequency (5, 3)	RSELx = 5, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.39		0.77	MHz
f _{DCO(6,3)}	DCO frequency (6, 3)	RSELx = 6, DCOx = 3, MODx = 0	2.2 V/3 V	0.54		1.06	MHz
f _{DCO(7,3)}	DCO frequency (7, 3)	RSELx = 7, DCOx = 3, MODx = 0	2.2 V/3 V	0.80		1.50	MHz
f _{DCO(8,3)}	DCO frequency (8, 3)	RSELx = 8, DCOx = 3, MODx = 0	2.2 V/3 V	1.10		2.10	MHz
f _{DCO(9,3)}	DCO frequency (9, 3)	RSELx = 9, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	1.60		3.00	MHz
f _{DCO(10,3)}	DCO frequency (10, 3)	RSELx = 10, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	2.50		4.30	MHz
f _{DCO(11,3)}	DCO frequency (11, 3)	RSELx = 11, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	3.00		5.50	MHz
f _{DCO(12,3)}	DCO frequency (12, 3)	RSELx = 12, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	4.30		7.30	MHz
f _{DCO(13,3)}	DCO frequency (13, 3)	RSELx = 13, DCOx = 3, MODx = 0	2.2 V/3 V	6.00		9.60	MHz
f _{DCO(14,3)}	DCO frequency (14, 3)	RSELx = 14, DCOx = 3, MODx = 0	2.2 V/3 V	8.60		13.9	MHz
f _{DCO(15,3)}	DCO frequency (15, 3)	RSELx = 15, DCOx = 3, MODx = 0	3 V	12.0		18.5	MHz
f _{DCO(15,7)}	DCO frequency (15, 7)	RSELx = 15, DCOx = 7, MODx = 0	3 V	16.0		26.0	MHz
S _{RSEL}	Frequency step between range RSEL and RSEL+1	$S_{RSEL} = f_{DCO(RSEL+1,DCO)}/f_{DCO(RSEL,DCO)}$	2.2 V/3 V			1.55	ratio
S _{DCO}	Frequency step between tap DCO and DCO+1	$S_{DCO} = f_{DCO(RSEL,DCO+1)}/f_{DCO(RSEL,DCO)}$	2.2 V/3 V	1.05	1.08	1.12	ratio
Duty cycle		Measured at P1.4/SMCLK	2.2 V/3 V	40	50	60	%

MSP430x241x, MSP430x261x MIXED SIGNAL MICROCONTROLLER

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

calibrated DCO frequencies - tolerance at calibration

	PARAMETER	TEST CONDITIONS	TA	VCC	MIN	TYP	MAX	UNIT
Frequency to	olerance at calibration		25°C	3 V	-1	±0.2	+1	%
fCAL(1MHz)	1-MHz calibration value	BCSCTL1 = CALBC1_1MHz, DCOCTL = CALDCO_1MHz, Gating time: 5 ms	25°C	3 V	0.990	1	1.010	MHz
fCAL(8MHz)	8-MHz calibration value	BCSCTL1 = CALBC1_8MHz, DCOCTL = CALDCO_8MHz, Gating time: 5ms	25°C	3 V	7.920	8	8.080	MHz
f _{CAL(12MHz)}	12-MHz calibration value	BCSCTL1 = CALBC1_12MHz, DCOCTL = CALDCO_12MHz, Gating time: 5ms	25°C	3 V	11.88	12	12.12	MHz
f _{CAL(16MHz)}	16-MHz calibration value	BCSCTL1 = CALBC1_16MHz, DCOCTL = CALDCO_16MHz, Gating time: 2 ms	25°C	3 V	15.84	16	16.16	MHz

calibrated DCO frequencies - tolerance over temperature 0°C to 85°C

	PARAMETER	TEST CONDITIONS	T _A	VCC	MIN	TYP	MAX	UNIT
1-MHz tolera	ance over temperature		0°C to 85°C	3 V	-2.5	±0.5	+2.5	%
8-MHz tolera	ance over temperature		0°C to 85°C	3 V	-2.5	±1.0	+2.5	%
12-MHz tole	rance over temperature		0°C to 85°C	3 V	-2.5	±1.0	+2.5	%
16-MHz tole	rance over temperature		0°C to 85°C	3 V	-3.0	±2.0	+3.0	%
		BCSCTL1 = CALBC1_1MHz,		2.2 V	0.970	1	1.030	
f _{CAL(1MHz)}	1-MHz calibration value	DCOCTL = CALDCO_1MHz,	0°C to 85°C	3 V	0.975	1	1.025	MHz
, .		Gating time: 5ms		3.6 V	0.970	1	1.030	
		BCSCTL1 = CALBC1_8MHz,		2.2 V	7.760	8	8.400	
f _{CAL(8MHz)}	8-MHz calibration value	DCOCTL = CALDCO_8MHz,	0°C to 85°C	3 V	7.800	8	8.200	MHz
		Gating time: 5 ms		3.6 V	7.600	8	8.240	
		BCSCTL1 = CALBC1 12MHz,		2.2 V	11.64	12	12.36	
f _{CAL(12MHz)}	12-MHz calibration value	DCOCTL = CALDCO_12MHz,	0°C to 85°C	3 V	11.64	12	12.36	MHz
5. IL(. LIVII IL)		Gating time: 5 ms		3.6 V	11.64	12	12.36	1
£	10 MHz calibration value	BCSCTL1 = CALBC1_16MHz, DCOCTL = CALDCO_16MHz,	0°C to 05°C	3 V	15.52	16	16.48	NAL 1-
[†] CAL(16MHz)	16-MHz calibration value	Gating time: 2 ms	0°C to 85°C	3.6 V	15.00	16	16.48	MHz

MSP430x241x, MSP430x261x MIXED SIGNAL MICROCONTROLLER

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

calibrated DCO frequencies - tolerance over supply voltage V_{CC}

PARAMETER	TEST CONDITIONS	T _A	vcc	MIN	TYP	MAX	UNIT
1-MHz tolerance over V _{CC}		25°C	1.8 V to 3.6 V	-3	±2	+3	%
8-MHz tolerance over V _{CC}		25°C	1.8 V to 3.6 V	-3	±2	+3	%
12-MHz tolerance over V _{CC}		25°C	2.2 V to 3.6 V	-3	±2	+3	%
16-MHz tolerance over V _{CC}		25°C	3.0 V to 3.6 V	-6	±2	+3	%
f _{CAL(1MHz)} 1-MHz calibration value	BCSCTL1 = CALBC1_1MHz, DCOCTL = CALDCO_1MHz, Gating time: 5 ms	25°C	1.8 V to 3.6 V	0.970	1	1.030	MHz
f _{CAL(8MHz)} 8-MHz calibration value	BCSCTL1 = CALBC1_8MHz, DCOCTL = CALDCO_8MHz, Gating time: 5 ms	25°C	1.8 V to 3.6 V	7.760	8	8.240	MHz
f _{CAL(12MHz)} 12-MHz calibration value	BCSCTL1 = CALBC1_12MHz, DCOCTL = CALDCO_12MHz, Gating time: 5 ms	25°C	2.2 V to 3.6 V	11.64	12	12.36	MHz
f _{CAL(16MHz)} 16-MHz calibration value	BCSCTL1 = CALBC1_16MHz, DCOCTL = CALDCO_16MHz, Gating time: 2 ms	25°C	3.0 V to 3.6 V	15.00	16	16.48	MHz

calibrated DCO frequencies - overall tolerance

	PARAMETER	TEST CONDITIONS	TA	vcc	MIN	TYP	MAX	UNIT
1-MHz tolera	ance overall		-40°C to 105°C	1.8 V to 3.6 V	-5	±2	+5	%
8-MHz tolera	ance overall		-40°C to 105°C	1.8 V to 3.6 V	-5	±2	+5	%
12-MHz tole	rance overall		-40°C to 105°C	2.2 V to 3.6 V	-5	±2	+5	%
16-MHz tole	rance overall		-40°C to 105°C	3 V to 3.6 V	-6	±3	+6	%
f _{CAL(1MHz)}	1-MHz calibration value	BCSCTL1 = CALBC1_1MHz, DCOCTL = CALDCO_1MHz, Gating time: 5ms	-40°C to 105°C	1.8 V to 3.6 V	0.950	1	1.050	MHz
f _{CAL(8MHz)}	8-MHz calibration value	BCSCTL1 = CALBC1_8MHz, DCOCTL = CALDCO_8MHz, Gating time: 5ms	-40°C to 105°C	1.8 V to 3.6 V	7.600	8	8.400	MHz
f _{CAL(12MHz)}	12-MHz calibration value	BCSCTL1 = CALBC1_12MHz, DCOCTL = CALDCO_12MHz, Gating time: 5ms	-40°C to 105°C	2.2 V to 3.6 V	11.40	12	12.60	MHz
f _{CAL(16MHz)}	16-MHz calibration value	BCSCTL1 = CALBC1_16MHz, DCOCTL = CALDCO_16MHz, Gating time: 2 ms	-40°C to 105°C	3 V to 3.6 V	15.00	16	17.00	MHz

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

typical characteristics - calibrated 1-MHz DCO frequency

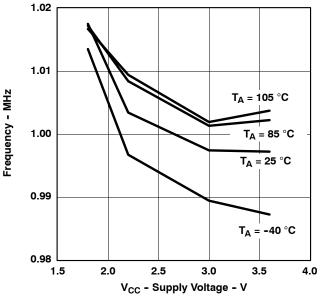


Figure 14. Calibrated 1-MHz Frequency vs V_{CC}

typical characteristics - calibrated 8-MHz DCO frequency

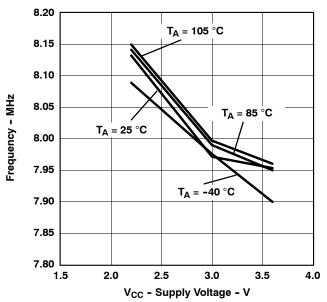


Figure 15. Calibrated 8-MHz Frequency vs V_{CC}



typical characteristics - calibrated 12-MHz DCO frequency

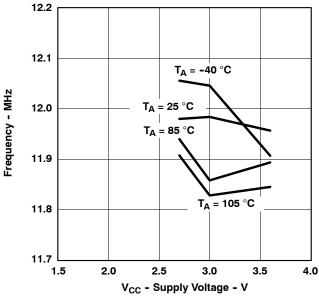


Figure 16. Calibrated 12-MHz Frequency vs V_{CC}

typical characteristics - calibrated 16-MHz DCO frequency

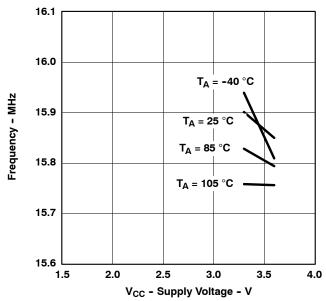


Figure 17. Calibrated 16-MHz Frequency vs V_{CC}

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

wake-up from low-power modes (LPM3/LPM4)

	PARAMETER	TEST CONDITIONS	VCC	MIN TYP	MAX	UNIT
		BCSCTL1= CALBC1_1MHz, DCOCTL = CALDCO_1MHz	2.2 V/3 V		2	
	DCO clock wake-up time from LPM3/4	BCSCTL1= CALBC1_8MHz, DCOCTL = CALDCO_8MHz	2.2 V/3 V		1.5	
^t DCO,LPM3/4	(see Note 1)	BCSCTL1= CALBC1_12MHz, DCOCTL = CALDCO_12MHz	2.2 V/3 V	V	1	μS
		BCSCTL1= CALBC1_16MHz, DCOCTL = CALDCO_16MHz	3 V		1	
t _{CPU,LPM3/4}	CPU wake-up time from LPM3/4 (see Note 2)			1/f _{MCLK} + t _{Clock,LPM3/4}	1	

NOTES: 1. The DCO clock wake-up time is measured from the edge of an external wake-up signal (e.g., port interrupt) to the first clock edge observable externally on a clock pin (MCLK or SMCLK).

typical characteristics - DCO clock wake-up time from LPM3/4

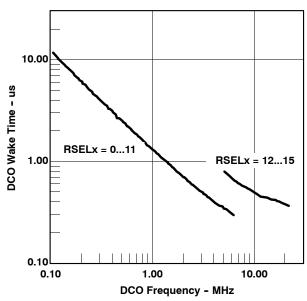


Figure 18. Clock Wake-Up Time From LPM3 vs DCO Frequency

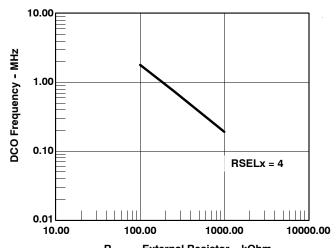
^{2.} Parameter applicable only if DCOCLK is used for MCLK.

DCO with external resistor R_{OSC} (see Note 1)

PARAMETER		TEST CONDITIONS	VCC	TYP	UNIT
f DCO output fraguancy with B		DCOR = 1, RSELx = 4, DCOx = 3, MODx = 0, T _A = 25°C	2.2 V	1.8	MHz
†DCO,ROSC	DCO output frequency with hosc	$\frac{1}{10000} = 1$, $\frac{1}{100000} = 4$, $\frac{1}{10000000000000000000000000000000000$	3 V	1.95	IVITZ
D _t	Temperature drift	DCOR = 1, RSELx = 4, DCOx = 3, MODx = 0	2.2 V/3 V	±0.1	%/°C
D_V	Drift with V _{CC}	DCOR = 1, RSELx = 4, DCOx = 3, MODx = 0	2.2 V/3 V	10	%/V

NOTE 1: $R_{OSC} = 100 \text{ k}\Omega$. Metal film resistor, type 0257. 0.6 watt with 1% tolerance and $T_{K} = \pm 50 \text{ppm}/^{\circ}\text{C}$.

typical characteristics - DCO with external resistor R_{OSC}



R_{OSC} - External Resistor - kOhm Figure 19. DCO Frequency vs R_{OSC}, $V_{CC} = 2.2 \text{ V}, \, \dot{T}_{A} = 25^{\circ}\text{C}$

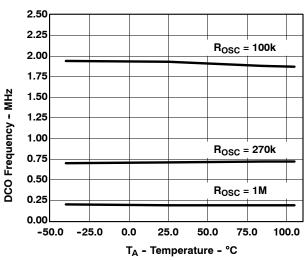


Figure 21. DCO Frequency vs Temperature, $V_{CC} = 3.0 V$

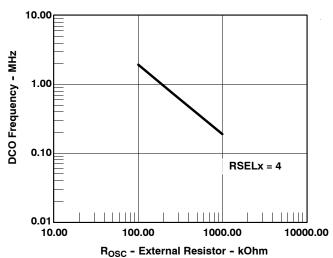


Figure 20. DCO Frequency vs R_{OSC} , V_{CC} = 3.0 V, T_A = 25°C

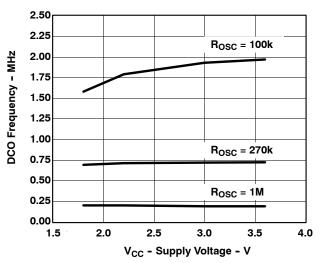


Figure 22. DCO Frequency vs V_{CC} , $T_A = 25^{\circ}C$

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

crystal oscillator, LFXT1, low frequency modes (see Note 4)

F	PARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	UNIT
f _{LFXT1,LF}	LFXT1 oscillator crystal frequency, LF mode 0/1	XTS = 0, LFXT1Sx = 0 or 1	1.8 V to 3.6 V		32,768		Hz
fLFXT1,LF,logic	LFXT1 oscillator logic level square wave input frequency, LF mode	XTS = 0, LFXT1Sx = 3, XCAPx = 0	1.8 V to 3.6 V	10,000	32,768	50,000	Hz
OALF	Oscillation allowance for LF crystals	$\begin{split} \text{XTS} &= 0, \text{LFXT1Sx} = 0, \\ \text{f}_{\text{LFXT1,LF}} &= 32,768 \text{kHz}, \\ \text{C}_{\text{L,eff}} &= 6 \text{pF} \end{split}$			500		kΩ
	LF Crystais	XTS = 0, LFXT1Sx = 0; f _{LFXT1,LF} = 32,768 kHz, C _{L,eff} = 12 pF					
		XTS = 0, XCAPx = 0			1		
	Integrated effective load	XTS = 0, XCAPx = 1]		5.5		_
$C_{L,eff}$	capacitance, LF mode (see Note 1)	XTS = 0, XCAPx = 2			8.5		pF
	(XTS = 0, XCAPx = 3]		11		
Duty cycle	LF mode	XTS = 0, Measured at P1.4/ACLK, f _{LFXT1,LF} = 32,768 Hz	2.2 V/3 V	30	50	70	%
f _{Fault,LF}	Oscillator fault frequency, LF mode (see Note 3)	XTS = 0, LFXT1Sx = 3, XCAPx = 0 (see Note 2)	2.2 V/3 V	10		10,000	Hz

NOTES: 1. Includes parasitic bond and package capacitance (approximately 2 pF per pin).

Since the PCB adds additional capacitance, it is recommended to verify the correct load by measuring the ACLK frequency. For a correct setup, the effective load capacitance should always match the specification of the used crystal.

- 2. Measured with logic level input frequency but also applies to operation with crystals.
- 3. Frequencies below the MIN specification will set the fault flag, frequencies above the MAX specification will not set the fault flag. Frequencies in between might set the flag.
- 4. To improve EMI on the LFXT1 oscillator the following guidelines should be observed.
 - Keep as short of a trace as possible between the device and the crystal.
 - Design a good ground plane around the oscillator pins.
 - Prevent crosstalk from other clock or data lines into oscillator pins XIN and XOUT.
 - Avoid running PCB traces underneath or adjacent to the XIN and XOUT pins.
 - Use assembly materials and praxis to avoid any parasitic load on the oscillator XIN and XOUT pins.
 - If conformal coating is used, ensure that it does not induce capacitive/resistive leakage between the oscillator pins.
 - Do not route the XOUT line to the JTAG header to support the serial programming adapter as shown in other documentation. This signal is no longer required for the serial programming adapter.
- 5. Applies only if using an external logic-level clock source. Not applicable when using a crystal or resonator.

MSP430x241x, MSP430x261x MIXED SIGNAL MICROCONTROLLER

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

internal very low power, low frequency oscillator (VLO)

F	PARAMETER	TEST CONDITIONS	T _A	VCC	MIN	TYP	MAX	UNIT
			-40°C to 85°C	0.034/034	4	12	20	
t∨LO	VLO frequency		105°C	2.2 V/3 V			22	kHz
df _{VLO} /dT	VLO frequency temperature drift	See Note NO TAG1		2.2 V/3 V		0.5		%/°C
df _{VLO} /dV _{CC}	VLO frequency supply voltage drift	See Note 2	25°C	1.8V - 3.6V		4		%/V

NOTES: 1. Calculated using the box method:

I version: (MAX(-40 $^{\circ}$ C to 85 $^{\circ}$ C) - MIN(-40 $^{\circ}$ C to 85 $^{\circ}$ C))/MIN(-40 $^{\circ}$ C to 85 $^{\circ}$ C)/(85 $^{\circ}$ C - (-40 $^{\circ}$ C))

T version: (MAX(-40°C to 105_C) - MIN(-40°C to 105_C))/MIN(-40°C to 105_C)/(105_C - (-40°C))

2. Calculated using the box method: (MAX(1.8 V to 3.6V) - MIN(1.8V to 3.6V))/MIN(1.8 V to 3.6V)/(3.6 V - 1.8 V)

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

crystal oscillator, LFXT1, high frequency modes (see Note 5)

	PARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	UNIT
f _{LFXT1,HF0}	LFXT1 oscillator crystal frequency, HF mode 0	XTS = 1, LFXT1Sx = 0, XCAPx = 0	1.8 V to 3.6 V	0.4		1	MHz
f _{LFXT1,HF1}	LFXT1 oscillator crystal frequency, HF mode 1	XTS = 1, LFXT1Sx = 1, XCAPx = 0	1.8 V to 3.6 V	1		4	MHz
			1.8 V to 3.6 V	2		10	
f _{LFXT1,HF2}	LFXT1 oscillator crystal frequency, HF mode 2	XTS = 1, LFXT1Sx = 2, XCAPx = 0	2.2 V to 3.6 V	2		12	MHz
	TH Mode 2		3 V to 3.6 V	2		16	
	LFXT1 oscillator logic level		1.8 V to 3.6 V	0.4		10	
fLFXT1,HF,logic	square-wave input frequency,	XTS = 1, LFXT1Sx = 3, XCAPx = 0	2.2 V to 3.6 V	0.4		12	MHz
	HF mode		3 V to 3.6 V	0.4		16	
		XTS = 1, XCAPx = 0, LFXT1Sx = 0, f _{LFXT1,HF} = 1 MHz, C _{L,eff} = 15 pF			2700		
OA _{HF}	Oscillation allowance for HF crystals (see Figure 23 and Figure 24)	XTS = 1, XCAPx = 0, LFXT1Sx = 1, f _{LFXT1,HF} = 4 MHz, C _{L,eff} = 15 pF			800		Ω
		XTS = 1, XCAPx = 0, LFXT1Sx = 2, f _{LFXT1,HF} = 16 MHz, C _{L,eff} = 15 pF			300		
$C_{L,eff}$	Integrated effective load capacitance, HF mode (see Note 1)	XTS = 1, XCAPx = 0 (see Note 2)			1		pF
Dutumala	UE made	XTS = 1, XCAPx = 0, Measured at P1.4/ACLK, f _{LFXT1,HF} = 10 MHz	2.2 V/3 V	40	50	60	0/
Duty cycle	HF mode	XTS = 1, XCAPx = 0, Measured at P1.4/ACLK, f _{LFXT1,HF} = 16 MHz	2.2 V/3 V	40	50	60	%
f _{Fault,HF}	Oscillator fault frequency, HF mode (see Note 4)	XTS = 1, LFXT1Sx = 3, XCAPx = 0 (see Note 3)	2.2 V/3 V	30		300	kHz

- NOTES: 1. Includes parasitic bond and package capacitance (approximately 2 pF per pin).
 - Since the PCB adds additional capacitance it is recommended to verify the correct load by measuring the ACLK frequency. For a correct setup the effective load capacitance should always match the specification of the used crystal.
 - 2. Requires external capacitors at both terminals. Values are specified by crystal manufacturers.
 - 3. Measured with logic level input frequency but also applies to operation with crystals.
 - 4. Frequencies below the MIN specification will set the fault flag, frequencies above the MAX specification will not set the fault flag. Frequencies in between might set the flag.
 - 5. To improve EMI on the LFXT1 oscillator the following guidelines should be observed.
 - Keep the trace between the device and the crystal as short as possible.
 - Design a good ground plane around the oscillator pins.
 - Prevent crosstalk from other clock or data lines into oscillator pins XIN and XOUT.
 - Avoid running PCB traces underneath or adjacent to the XIN and XOUT pins.
 - Use assembly materials and praxis to avoid any parasitic load on the oscillator XIN and XOUT pins.
 - If conformal coating is used, ensure that it does not induce capacitive/resistive leakage between the oscillator pins.
 - Do not route the XOUT line to the JTAG header to support the serial programming adapter as shown in other documentation. This signal is no longer required for the serial programming adapter.



typical characteristics - LFXT1 oscillator in HF mode (XTS = 1)

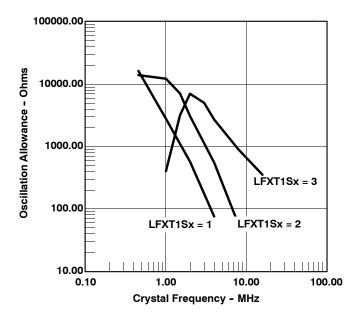


Figure 23. Oscillation Allowance vs Crystal Frequency, $C_{L,eff}$ = 15 pF, T_A = 25°C

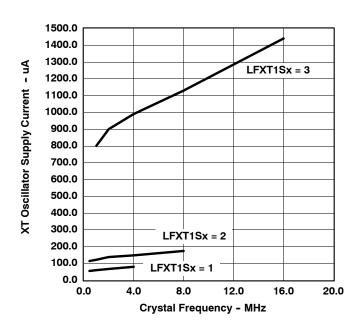


Figure 24. XT Oscillator Supply Current vs Crystal Frequency, $C_{L,eff}$ = 15 pF, T_A = 25 $^{\circ}$ C



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

crystal oscillator, XT2 (see Note 5)

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
f _{XT2}	XT2 oscillator crystal frequency, mode 0	XT2Sx = 0	1.8 V to 3.6 V	0.4		1	MHz
f _{XT2}	XT2 oscillator crystal frequency, mode 1	XT2Sx = 1	1.8 V to 3.6 V	1		4	MHz
			1.8 V to 3.6 V	2		10	
f _{XT2}	XT2 oscillator crystal frequency, mode 2	XT2Sx = 2	2.2 V to 3.6 V	2		12	MHz
	mode 2		3 V to 3.6 V	2		16	
			1.8 V to 3.6 V	0.4		10	
f _{XT2}	XT2 oscillator logic level square-wave input frequency	XT2Sx = 3	2.2 V to 3.6 V	0.4		12	MHz
	equate wave input frequency		3 V to 3.6 V	0.4		16	
		XT2Sx = 0, f _{XT2} = 1 MHz, C _{L,eff} = 15 pF			2700		
OA	Oscillation allowance (see Figure 23 and Figure 24)	XT2Sx = 1, f _{XT2} = 4 MHz, C _{L,eff} = 15 pF			800		Ω
		XT2Sx = 2, f _{XT1,HF} = 16 MHz, C _{L,eff} = 15 pF			300		
$C_{L,eff}$	Integrated effective load capacitance, HF mode (see Note 1)	See Note 2			1		pF
D. I I.		Measured at P1.4/SMCLK, f _{XT2} = 10 MHz	0.07//07/	40	50	60	٠,
Duty cycle		Measured at P1.4/SMCLK, f _{XT2} = 16 MHz	2.2 V/3 V	40	50	60	%
f _{Fault}	Oscillator fault frequency, HF mode (see Note 4)	XT2Sx = 3, (see Note 3)	2.2 V/3 V	30		300	kHz

NOTES: 1. Includes parasitic bond and package capacitance (approximately 2 pF per pin).

Since the PCB adds additional capacitance, it is recommended to verify the correct load by measuring the ACLK frequency. For a correct setup, the effective load capacitance should always match the specification of the used crystal.

- 2. Requires external capacitors at both terminals. Values are specified by crystal manufacturers.
- 3. Measured with logic level input frequency but also applies to operation with crystals.
- Frequencies below the MIN specification will set the fault flag, frequencies above the MAX specification will not set the fault flag.
- 5. To improve EMI on the LFXT1 oscillator the following guidelines should be observed.
 - Keep the trace between the device and the crystal as short as possible.
 - Design a good ground plane around the oscillator pins.
 - Prevent crosstalk from other clock or data lines into oscillator pins XIN and XOUT.
 - Avoid running PCB traces underneath or adjacent to the XIN and XOUT pins.
 - Use assembly materials and praxis to avoid any parasitic load on the oscillator XIN and XOUT pins.
 - If conformal coating is used, ensure that it does not induce capacitive/resistive leakage between the oscillator pins.
 - Do not route the XOUT line to the JTAG header to support the serial programming adapter as shown in other documentation. This signal is no longer required for the serial programming adapter.



typical characteristics - XT2 oscillator

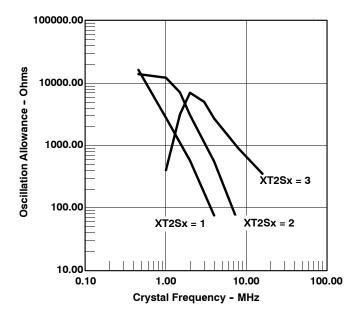


Figure 25. Oscillation Allowance vs Crystal Frequency, $C_{L,eff}$ = 15 pF, T_A = 25°C

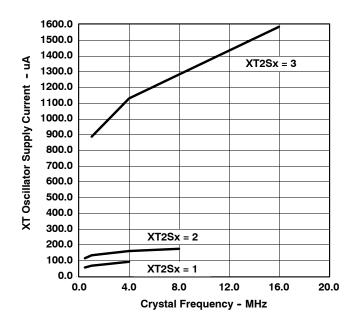


Figure 26. XT2 Oscillator Supply Current vs Crystal Frequency, $C_{L,eff}$ = 15 pF, T_A = 25 $^{\circ}$ C



MSP430x241x, MSP430x261x MIXED SIGNAL MICROCONTROLLER

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

Timer_A

PARAMETER		TEST CONDITIONS	VCC	MIN MAX	UNIT
4	Timer A clock frequency	Internal: SMCLK, ACLK,	2.2 V	10	MHz
f _{TA}	Timer_A clock frequency	External: TACLK, INCLK, Duty cycle = 50% ±10%	3.3 V	16	IVITIZ
t _{TA,cap}	Timer_A, capture timing	TA0, TA1, TA2	2.2 V/3 V	20	ns

Timer_B

PARAMETER		TEST CONDITIONS	VCC	MIN MAX	UNIT
£	Internal: SMCLK, ACLK, Timer B clock frequency External: TBCLK,		10	MHz	
ТТВ	Timer_B clock frequency	Duty cycle = 50% ±10%	3.3 V	16	IVITIZ
t _{TB,cap}	Timer_B, capture timing	TB0, TB1, TB2	2.2 V/3 V	20	ns



USCI (UART mode)

PARAMETER		TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
f _{USCI}	USCI input clock frequency	Internal: SMCLK, ACLK External: UCLK Duty cycle = 50% ± 10%		fsysтем			MHz
f _{BITCLK}	BITCLK clock frequency (equals baud rate in MBaud)		2.2 V /3 V			1	MHz
	UART receive deglitch time		2.2 V	50	150	600	ns
ττ	(see Note 1)		3 V	50	100	600	ns

NOTE 1: Pulses on the UART receive input (UCxRX) shorter than the UART receive deglitch time are suppressed. To ensure that pulses are correctly recognized their width should exceed the maximum specification of the deglitch time.

USCI (SPI master mode) (see Figure 27 and Figure 28)

	PARAMETER	TEST CONDITIONS	VCC	MIN	MAX	UNIT
f _{USCI}	USCI input clock frequency	SMCLK, ACLK Duty cycle = 50% ± 10%			f _{SYSTEM}	MHz
	2011:		2.2 V	110		
t _{SU,MI}	SOMI input data setup time		3 V	75		ns
	OOM to a data hald to a		2.2 V	0		
t _{HD,MI}	SOMI input data hold time		3 V	0		ns
	0040	UCLK edge to SIMO valid;	2.2 V		30	
t _{VALID,MO}	SIMO output data valid time	C _L = 20 pF	3 V		20	ns

 $\text{NOTE 2:} \quad f_{\text{UCxCLK}} = \frac{1}{2t_{\text{LO/HI}}} \text{ with } t_{\text{LO/HI}} \geq \\ \\ \text{max}(t_{\text{VALID,MO(USCI)}} + t_{\text{SU,SI(Slave)}}, t_{\text{SU,MI(USCI)}} + t_{\text{VALID,SO(Slave)}}). \\$

For the slave parameters $t_{SU,SI(Slave)}$ and $t_{VALID,SO(Slave)}$, see the SPI parameters of the attached slave.

USCI (SPI slave mode) (see Figure 29 and Figure 30)

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
t _{STE,LEAD}	STE lead time, STE low to clock		2.2 V/3 V		50		ns
t _{STE,LAG}	STE lag time, Last clock to STE high		2.2 V/3 V	10			ns
t _{STE,ACC}	STE access time, STE low to SOMI data out		2.2 V/3 V		50		ns
t _{STE,DIS}	STE disable time, STE high to SOMI high impedance		2.2 V/3 V		50		ns
			2.2 V	20			
t _{SU,SI}	SIMO input data setup time		3 V	15			ns
			2.2 V	10			
t _{HD,SI}	SIMO input data hold time		3 V	10			ns
		UCLK edge to SOMI valid;	2.2 V		75	110	
t _{VALID} ,SO	SOMI output data valid time	C _L = 20 pF	3 V		50	75	ns

 $\text{NOTE 3:} \quad f_{\text{UCxCLK}} = \frac{1}{2t_{\text{LO/HI}}} \text{ with } t_{\text{LO/HI}} \geq \\ \\ \text{max}(t_{\text{VALID,MO(Master)}} + t_{\text{SU,SI(USCI)}}, \\ \\ t_{\text{SU,MI(Master)}} + t_{\text{VALID,SO(USCI)}}) \\ \\ \text{NOTE 3:} \quad f_{\text{UCxCLK}} = \frac{1}{2t_{\text{LO/HI}}} \\ \\ \text{with } t_{\text{LO/HI}} \geq \\ \\ \text{max}(t_{\text{VALID,MO(Master)}} + t_{\text{SU,SI(USCI)}}, \\ \\ t_{\text{SU,MI(Master)}} + t_{\text{VALID,SO(USCI)}}) \\ \\ \text{NOTE 3:} \quad f_{\text{UCxCLK}} = \\ \\ \text{NOTE 3:} \\ \\ \text{N$

For the master parameters t_{SU,MI(Master)} and t_{VALID,MO(Master)}, see the SPI parameters of the attached master.



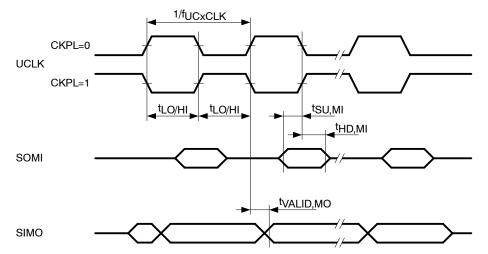


Figure 27. SPI Master Mode, CKPH = 0

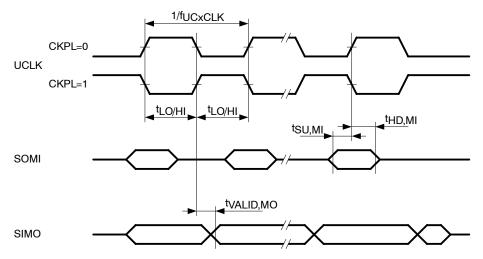


Figure 28. SPI Master Mode, CKPH = 1

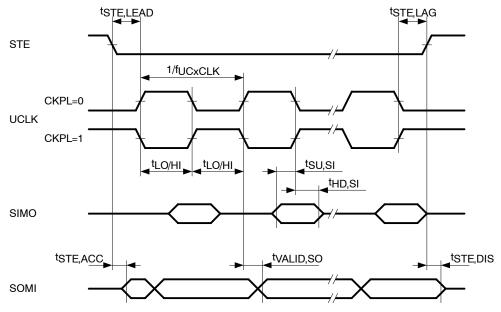


Figure 29. SPI Slave Mode, CKPH = 0

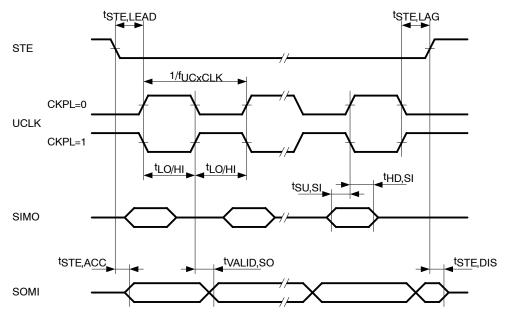


Figure 30. SPI Slave Mode, CKPH = 1

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

USCI (I2C mode) (see Figure 31)

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
fusci	USCI input clock frequency	Internal: SMCLK, ACLK External: UCLK Duty cycle = 50% ± 10%			f _S	SYSTEM	MHz
f _{SCL}	SCL clock frequency		2.2 V/3 V	0		400	kHz
	Hald Free Area at all Ota d	f _{SCL} ≤ 100 kHz	0.01//01/	4.0			
t _{HD,STA}	Hold time (repeated) Start	f _{SCL} > 100 kHz	2.2 V/3 V 0.6				μS
	Cation times for a variation Chart	f _{SCL} ≤ 100 kHz	0.01//01/	4.7			
t _{SU,STA}	Setup time for a repeated Start	f _{SCL} > 100 kHz	2.2 V/3 V	0.6			μS
t _{HD,DAT}	Data hold time		2.2 V/3 V	0			ns
t _{SU,DAT}	Data setup time		2.2 V/3 V	250			ns
t _{SU,STO}	Setup time for Stop		2.2 V/3 V	4.0			μs
	P. Lee, Miller Could are a considerable for a City		2.2 V	50	150	600	
t _{SP}	Pulse width of spikes suppressed by input filter		3 V	50	100	600	ns

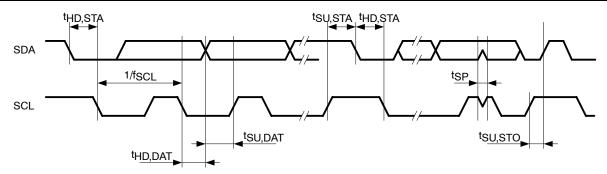


Figure 31. I2C Mode Timing

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

Comparator_A+ (see Note 1)

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
1		CAON = 1, CARSEL = 0, CAREF = 0	2.2 V		25	40	μΑ
I _(DD)		CAON = 1, CANGEL = 0, CANEL = 0	3 V		45	60	μΑ
		CAON = 1, CARSEL = 0,	2.2 V		30	50	^
(Refladder/Re	efdiode)	CAREF = 1/2/3, no load at P2.3/CA0/TA1 and P2.4/CA1/TA2	3 V		45	71	μΑ
V _(IC)	Common-mode input voltage	CAON =1	2.2 V/3 V	0		V _{CC} -1	V
V _(Ref025)	Voltage @ 0.25 V _{CC} node	PCA0 = 1, CARSEL = 1, CAREF = 1, no load at P2.3/CA0/TA1 and P2.4/CA1/TA2	2.2 V/3 V	0.23	0.24	0.25	
V _(Ref050)	Voltage @ 0.5V _{CC} node	PCA0 = 1, CARSEL = 1, CAREF = 2, no load at P2.3/CA0/TA1 and P2.4/CA1/TA2	2.2 V/3 V	0.47	0.48	0.5	
.,		PCA0 = 1, CARSEL = 1, CAREF = 3,	2.2 V	390	480	540	
$V_{(RefVT)}$	See Figure 35 and Figure 36	no load at P2.3/CA0/TA1 and P2.4/CA1/TA2, T _A = 85°C	3 V	400	490	550	mV
V _(offset)	Offset voltage	See Note 2	2.2 V/3 V	-30		30	mV
V _{hys}	Input hysteresis	CAON=1	2.2 V/3 V	0	0.7	1.4	mV
		T _A = 25°C, Overdrive 10 mV,	2.2 V	80	165	300	200
	Response time, low-to-high and	Without filter: CAF = 0	3 V	70	120	240	ns
t _(response)		T _A = 25°C, Overdrive 10 mV,	2.2 V	1.4	1.9	2.8	
		With filter: CAF = 1	3 V	0.9	1.5	2.2	μS



NOTES: 1. The leakage current for the Comparator_A+ terminals is identical to $I_{lkg(Px.x)}$ specification.

^{2.} The input offset voltage can be cancelled by using the CAEX bit to invert the Comparator_A+ inputs on successive measurements. The two successive measurements are then summed together.

^{3.} The response time is measured at P2.2/CAOUT/TA0/CA4 with an input voltage step, with Comparator A+ already enabled (CAON = 1). If CAON is set at the same time, a settling time of up to 300 ns is added to the response time.

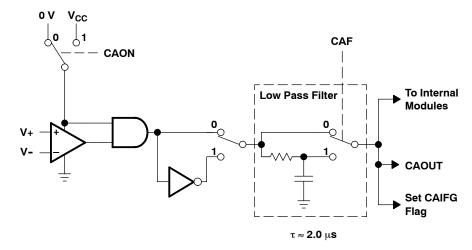


Figure 32. Block Diagram of Comparator_A Module

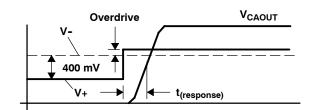


Figure 33. Overdrive Definition

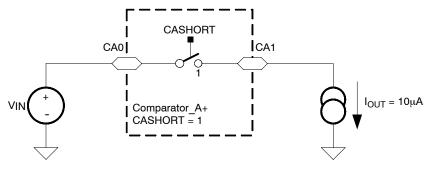
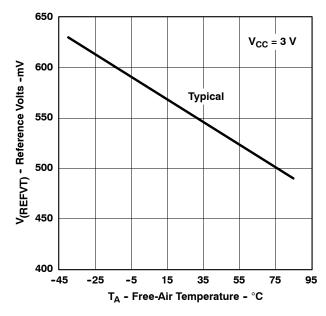


Figure 34. Comparator_A+ Short Resistance Test Condition

typical characteristics - Comparator A+



650 V_{CC} = 2.2 V V_{CC} = 2.2 V Typical 550 400 400 -45 -25 -5 15 35 55 75 95 T_A - Free-Air Temperature - °C

Figure 35. $V_{(RefVT)}$ vs Temperature, $V_{CC} = 3 V$

Figure 36. $V_{(RefVT)}$ vs Temperature, V_{CC} = 2.2 V

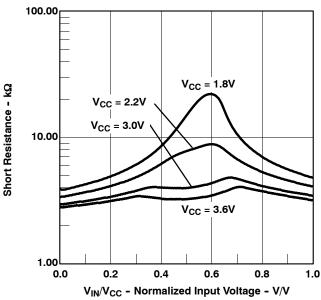


Figure 37. Short Resistance vs V_{IN}/V_{CC}

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

12-bit ADC power supply and input range conditions (see Note 1)

	PARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	UNIT
AV _{CC}	Analog supply voltage	AV _{CC} and DV _{CC} are connected together, AV _{SS} and DV _{SS} are connected together, $V_{(AVSS)} = V_{(DVSS)} = 0 V$		2.2		3.6	V
V _(P6.x/Ax)	Analog input voltage (see Note 2)	All P6.0/A0 to P6.7/A7 terminals. Analog inputs selected in ADC12MCTLx register and P6Sel.x = 1, $0 \le x \le 7$, $V_{(AVSS)} \le V_{P6.x/Ax} \le V_{(AVCC)}$		0		V _{AVCC}	٧
Operating supply current	f _{ADC12CLK} = 5 MHz, ADC12ON = 1, REFON = 0,	2.2 V		0.65	8.0		
I _{ADC12}	into AV _{CC} terminal (see Note 3)	SHT0 = 0, SHT1 = 0, ADC12DIV = 0	3 V		0.8	1.0	mA
	Operating supply current	f _{ADC12CLK} = 5 MHz, ADC12ON = 0, REFON = 1, REF2_5V = 1	3 V		0.5	0.7	
I _{REF+}	into AV _{CC} terminal (see Note 4)	f _{ADC12CLK} = 5 MHz, ADC12ON = 0,	2.2 V		0.5	0.7	mA
	(366 14016 4)	REFON = 1, REF2_5V = 0	3 V		0.5	0.7	
C _I †	Input capacitance	Only one terminal can be selected at one time, P6.x/Ax	2.2 V			40	pF
R _I †	Input MUX ON resistance	$0 \text{ V} \leq V_{Ax} \leq V_{AVCC}$	3 V			2000	Ω

[†] Lmits verified by design

NOTES: 1. The leakage current is defined in the leakage current table with P6.x/Ax parameter.

- 2. The analog input voltage range must be within the selected reference voltage range V_{R+} to V_{R-} for valid conversion results.
- 3. The internal reference supply current is not included in current consumption parameter I_{ADC12}.
- 4. The internal reference current is supplied via terminal AV_{CC}. Consumption is independent of the ADC12ON control bit, unless a conversion is active. The REFON bit enables to settle the built-in reference before starting an A/D conversion.

12-bit ADC external reference (see Note 1)

PARAM	METER	TEST CONDITIONS	VCC	MIN	MAX	UNIT
V _{eREF+}	Positive external reference voltage input	V _{eREF+} > V _{REF-} /V _{eREF-} (see Note 2)		1.4	V _{AVCC}	>
V _{REF-} /V _{eREF-}	Negative external reference voltage input	V _{eREF+} > V _{REF-} /V _{eREF-} (see Note 3)		0	1.2	V
(V _{eREF+} - V _{REF-} /V _{eREF-})	Differential external reference voltage input	V _{eREF+} > V _{REF-} /V _{eREF-} (see Note 4)		1.4	V _{AVCC}	V
I _{VeREF+}	Static input current	0V ≤V _{eREF+} ≤ V _{AVCC}	2.2 V/3 V		±1	μΑ
I _{VREF-/VeREF-}	Static input current	0V ≤ V _{eREF-} ≤ V _{AVCC}	2.2 V/3 V		±1	μΑ

- NOTES: 1. The external reference is used during conversion to charge and discharge the capacitance array. The input capacitance, C_i, is also the dynamic load for an external reference during conversion. The dynamic impedance of the reference supply should follow the recommendations on analog-source impedance to allow the charge to settle for 12-bit accuracy.
 - 2. The accuracy limits the minimum positive external reference voltage. Lower reference voltage levels may be applied with reduced accuracy requirements.
 - The accuracy limits the maximum negative external reference voltage. Higher reference voltage levels may be applied with reduced accuracy requirements.
 - 4. The accuracy limits minimum external differential reference voltage. Lower differential reference voltage levels may be applied with reduced accuracy requirements.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

12-bit ADC built-in reference

PA	RAMETER	TEST CONDITIONS	vcc	TA	MIN	TYP	MAX	UNIT
		REF2_5V = 1 (2.5 V)	0.14	-40°C to 85°C	2.4	2.5	2.6	
	Positive built-in	I _{VREF+} max ≤ I _{VREF+} ≤ I _{VREF+} min	3 V	105°C	2.37	2.5	2.64	v
V_{REF+}	reference voltage output	REF2_5V = 0 (1.5 V)	2.2 V/3 V	-40°C to 85°C	1.44	1.5	1.56	٧
	•	I _{VREF+} max ≤ I _{VREF+} ≤ I _{VREF+} min	2.2 V/3 V	105°C	1.42	1.5	1.57	
	AV _{CC} minimum	REF2_5V = 0, I_{VREF+} max $\leq I_{VREF+} \leq I_{VREF+}$ min			2.2			
AV _{CC(min)}	voltage, positive built-in reference	REF2_5V = 1, -0.5mA \leq I _{VREF+} \leq I _{VREF+} min			2.8			V
	active	REF2_5V = 1, -1mA ≤ I _{VREF+} ≤ I _{VREF+} min			2.9			
	Load current out of		2.2 V		0.01		-0.5	A
I _{VREF+}	V _{REF+} terminal		3 V		0.01		-1	mA
	I _{VREF+} = 500 μA +/- 100 μA Analog input voltage ~0.75 V,	2.2 V				±2		
	Load-current	REF2_5V = 0	3 V				±2	1.00
I _{L(VREF)+} †	regulation, V _{REF+} terminal	I _{VREF+} = 500 μA ± 100 μA Analog input voltage ~1.25 V, REF2_5V = 1	3 V				±2	LSB
I _{DL(VREF) +} ‡	Load current regulation V _{REF+} terminal	I_{VREF+} = 100 μA \rightarrow 900 μA, C_{VREF+} = 5 μF, at ~0.5 V_{REF+} , Error of conversion result ≤ 1 LSB	3 V				20	ns
C _{VREF+}	Capacitance at pin V _{REF+} (see Note 1)	REFON =1, 0 mA \leq I _{VREF+} \leq I _{VREF+} max	2.2 V/3 V		5	10		μF
T _{REF+} †	Temperature coefficient of built-in reference	I _{VREF+} is a constant in the range of 0 mA ≤ I _{VREF+} ≤ 1 mA	2.2 V/3 V				±100	ppm/°C
^t REFON [†]	Settle time of internal reference voltage (see Figure 38 and Note 2)	$I_{VREF+} = 0.5 \text{ mA, } C_{VREF+} = 10 \mu\text{F,}$ $V_{REF+} = 1.5 \text{ V, } V_{AVCC} = 2.2 \text{ V}$					17	ms

[†] Limits characterized



[‡] Limits verified by design

NOTES: 1. The internal buffer operational amplifier and the accuracy specifications require an external capacitor. All INL and DNL tests use two capacitors between pins V_{REF+} and AV_{SS} and V_{REF-}/V_{eREF-} and AV_{SS} : 10 μF tantalum and 100 nF ceramic.

^{2.} The condition is that the error in a conversion started after t_{REFON} is less than ± 0.5 LSB. The settling time depends on the external capacitive load.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

typical characteristics - ADC12

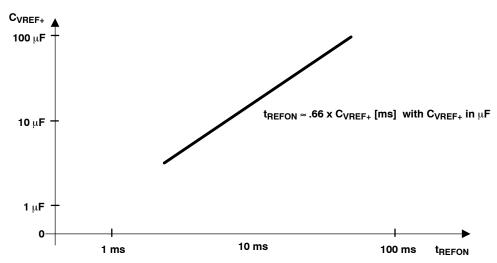


Figure 38. Typical Settling Time of Internal Reference t_{REFON} vs External Capacitor on V_{REF} +



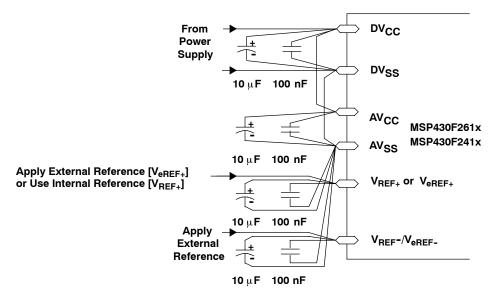


Figure 39. Supply Voltage and Reference Voltage Design $V_{\text{REF-}}/V_{\text{eREF-}}$ External Supply

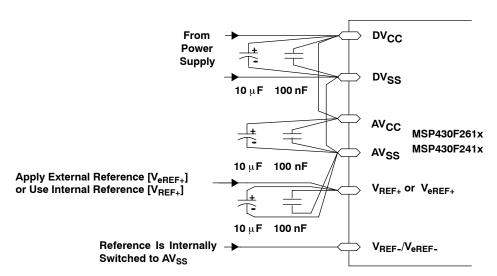


Figure 40. Supply Voltage and Reference Voltage Design V_{REF-}/V_{eREF-} = AV_{SS}, Internally Connected

MSP430x241x, MSP430x261x MIXED SIGNAL MICROCONTROLLER

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

12-bit ADC timing parameters

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
f _{ADC12CLK}		For specified performance of ADC12 linearity parameters	2.2V/3 V	0.45	5	6.3	MHz
f _{ADC12OSC}	Internal ADC12 oscillator	ADC12DIV = 0, fADC12CLK = fADC12OSC	2.2 V/ 3 V	3.7	5	6.3	MHz
	Conversion time	$C_{VREF+} \ge 5 \mu F$, Internal oscillator, $f_{ADC12OSC} = 3.7 \text{ MHz}$ to 6.3 MHz	2.2 V/ 3 V	2.06	3.51		
†CONVERT		External f _{ADC12CLK} from ACLK, MCLK or SMCLK, ADC12SSEL ≠ 0			13 × ADC12DIV × 1/f _{ADC12CLK}		μS
t _{ADC12ON} ‡	Turn-on settling time of the ADC	See Note 1				100	ns
+ ±		$R_S = 400 \Omega$, $R_I = 1000 \Omega$, $C_I = 30 pF$,	3 V	1220			no
t _{Sample} ‡		$\tau = [R_S + R_I] \times C_{I}$ (see Note 2)	2.2 V	1400			ns

[†] Limits characterized

NOTES: 1. The condition is that the error in a conversion started after t_{ADC12ON} is less than ±0.5 LSB. The reference and input signal are already settled.

2. Approximately ten Tau (τ) are needed to get an error of less than ± 0.5 LSB: $t_{Sample} = ln(2^{n+1}) \times (R_S + R_I) \times C_I + 800$ ns where n = ADC resolution = 12, $R_S =$ external source resistance.

12-bit ADC linearity parameters

PARAMETER		TEST CONDITIONS	vcc	MIN	TYP	MAX	UNIT
		$1.4 \text{ V} \le (V_{\text{eREF+}} - V_{\text{REF-}}/V_{\text{eREF-}}) \text{ min } \le 1.6 \text{ V}$	0.03//03/			±2	- OD
EI	Integral linearity error	1.6 V < (V _{eREF+} - V _{REF-} /V _{eREF-}) min ≤ V _{AVCC}	2.2 V/3 V			±1.7	LSB
E _D	Differential linearity error	$ \begin{array}{l} (V_{eREF+} - V_{REF-}/V_{eREF-})_{min} \leq (V_{eREF+} - V_{REF-}/V_{eREF-}), \\ C_{VREF+} = 10~\mu F ~(tantalum) ~and ~100~nF ~(ceramic) \end{array} $	2.2 V/3 V			±1	LSB
Eo	Offset error	$\begin{split} &(V_{eREF+} - V_{REF-}/V_{eREF-})_{min} \leq (V_{eREF+} - V_{REF-}/V_{eREF-}), \\ &\text{Internal impedance of source } R_S < 100 \ \Omega, \\ &C_{VREF+} = 10 \ \mu F \ (tantalum) \ and \ 100 \ nF \ (ceramic) \end{split}$	2.2 V/3 V		±2	±4	LSB
E _G	Gain error	$ \begin{array}{l} (V_{\text{eREF+}} - V_{\text{REF-}}/V_{\text{eREF-}})_{\text{min}} \leq (V_{\text{eREF+}} - V_{\text{REF-}}/V_{\text{eREF-}}), \\ C_{\text{VREF+}} = 10~\mu\text{F (tantalum) and } 100~\text{nF (ceramic)} \end{array} $	2.2 V/3 V		±1.1	±2	LSB
E _T	Total unadjusted error	$(V_{\text{eREF+}} - V_{\text{REF-}}/V_{\text{eREF-}})_{\text{min}} \le (V_{\text{eREF+}} - V_{\text{REF-}}/V_{\text{eREF-}}),$ $C_{\text{VREF+}} = 10~\mu\text{F}$ (tantalum) and 100 nF (ceramic)	2.2 V/3 V		±2	±5	LSB



[‡] Limits verified by design

electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

12-bit ADC temperature sensor and built-in V_{MID}

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
•	Operating supply current into	REFON = 0, INCH = 0Ah,	2.2 V		40	120	
ISENSOR	AV _{CC} terminal (see Note 1)	ADC12ON = 1, T _A = 25°C	3 V		60	160	μΑ
\/ +	Con Note O	ADC12ON = 1, INCH = 0Ah,	2.2 V		986		\/
V _{SENSOR} †	See Note 2	T _A = 0°C	3 V		986		mV
TO t			2.2 V		3.55		mV/°C
TC _{SENSOR} †		ADC12ON = 1, INCH = 0Ah	3 V		3.55		
+	Sample time required if channel 10 is selected (see Note 3)	ADC12ON = 1, INCH = 0Ah, Error of conversion result ≤ 1 LSB	2.2 V	30			_
t _{SENSOR(sample)} †			3 V	30			μS
	Current into divider at channel 11	ADOLOGNI A INIGILI ODI	2.2 V			NA	
IVMID	(see Note 4)	ADC12ON = 1, INCH = 0Bh	3 V			NA	μΑ
V	AV divides at absence 44	ADC12ON = 1, INCH = 0Bh,	2.2 V		1.1	1.1±0.04	V
V _{MID}	AV _{CC} divider at channel 11	V _{MID} is ~0.5 x V _{AVCC}	3 V		1.5	1.50±0.04	V
.	Sample time required if channel	ADC12ON = 1, INCH = 0Bh,	2.2 V	1400			20
t _{VMID} (sample)	11 is selected (see Note 5)	Error of conversion result ≤ 1 LSB	3 V	1220	•	•	ns

[†] Limits characterized

NOTES: 1. The sensor current I_{SENSOR} is consumed if (ADC12ON = 1 and REFON = 1) or if (ADC12ON = 1, INCH = 0Ah and sample signal is high). When REFON = 1, I_{SENSOR} is already included in I_{REF+}.

- 2. The temperature sensor offset can be as much as ±20°C. A single-point calibration is recommended in order to minimize the offset error of the built-in temperature sensor.
- 3. The typical equivalent impedance of the sensor is 51 k Ω . The sample time required includes the sensor-on time $t_{SENSOR(on)}$.
- 4. No additional current is needed. The $V_{\mbox{\scriptsize MID}}$ is used during sampling.
- 5. The on time $t_{VMID(on)}$ is included in the sampling time $t_{VMID(sample)}$; no additional on time is needed.



MSP430x241x, MSP430x261x MIXED SIGNAL MICROCONTROLLER

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

12-bit DAC supply specifications

	PARAMETER	TEST CONDITIONS	vcc	TA	MIN	TYP	MAX	UNIT
AV _{CC}	Analog supply voltage	$AV_{CC} = DV_{CC},$ $AV_{SS} = DV_{SS} = 0 V$			2.20		3.60	V
		DAC12AMPx = 2, DAC12IR = 0,	0.01/01/	-40°C to 85°C		50	110	
		DAC12_xDAT = 0x0800	2.2V/3V	105°C		69	150	
	Supply current, single	DAC12AMPx = 2, DAC12IR = 1, DAC12_xDAT = x00800 , V _{eREF+} = V _{REF+} = AV _{CC}	2.2V/3V			50	130	
I _{DD}	DAC channel (see Notes 1 and 2)	DAC12AMPx = 5, DAC12IR = 1, DAC12_xDAT = 0x0800, V _{eREF+} = V _{REF+} = AV _{CC}	2.2V/3V			200	440	μΑ
		DAC12AMPx = 7, DAC12IR = 1, DAC12_xDAT = 0x0800, V _{eREF+} = V _{REF+} = AV _{CC}	2.2V/3V			700	1500	
PSRR	Power-supply rejection ratio (see Notes 3 and 4)	DAC12_xDAT = 800h, V _{REF} = 1.5 V, ΔAV _{CC} = 100mV	2.2V			70		ī
		DAC12_xDAT = 800h, V _{REF} = 1.5 V or 2.5 V, ΔAV _{CC} = 100mV	3V			70		dB

NOTES: 1. No load at the output pin, DAC12_0 or DAC12_1, assuming that the control bits for the shared pins are set properly.

- 3. $PSRR = 20 \times log{\Delta AV_{CC}/\Delta V_{DAC12_xOUT}}$
- 4. $V_{\mbox{\scriptsize REF}}$ is applied externally. The internal reference is not used.



^{2.} Current into reference terminals not included. If DAC12IR = 1 current flows through the input divider; see Reference Input specifications.

electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

12-bit DAC linearity specifications (see Figure 41)

PARAMETER		TEST CONDITIONS	vcc	MIN	TYP	MAX	UNIT
	Resolution	12-bit monotonic		12			bits
INII		V _{REF} = 1.5 V DAC12AMPx = 7, DAC12IR = 1	2.2 V		0.0	0.0	1.00
INL	Integral nonlinearity (see Note 1)	V _{REF} = 2.5 V DAC12AMPx = 7, DAC12IR = 1	3 V		±2.0	±8.0	LSB
DNII	Differential nonlinearity	V _{REF} = 1.5 V DAC12AMPx = 7, DAC12IR = 1	2.2 V		±0.4	10	- 00
DNL	(see Note 1)	V _{REF} = 2.5 V DAC12AMPx = 7, DAC12IR = 1	3 V	3 V		±1.0	LSB
	Offset voltage without calibration (see Notes 1 and 2) Offset voltage with calibration (see Notes 1 and 2)	V _{REF} = 1.5 V DAC12AMPx = 7, DAC12IR = 1	2.2 V			0.4	
E _O		V _{REF} = 2.5 V DAC12AMPx = 7, DAC12IR = 1	3 V			±21	\/
		V _{REF} = 1.5 V DAC12AMPx = 7, DAC12IR = 1	2.2 V			0.5	mV
		V _{REF} = 2.5 V DAC12AMPx = 7, DAC12IR = 1	3 V			±2.5	
d _{E(O)} /d _T	Offset error temperature coefficient (see Note 1)		2.2 V/3 V		30		μV/C
_	Octobra Malad	V _{REF} = 1.5 V	2.2 V				۲ FOD
E _G	Gain error (see Note 1)	V _{REF} = 2.5 V	3 V			±3.50	% FSR
d _{E(G)} /d _T	Gain temperature coefficient (see Note 1)		2.2 V/3 V		10		ppm of FSR/°C
		DAC12AMPx = 2				100	
t _{Offset} Cal	Time for offset calibration (see Note 3)	DAC12AMPx = 3, 5	2.2 V/3 V			32	ms
	(555 : 1516 5)	DAC12AMPx = 4, 6, 7				6	

- NOTES: 1. Parameters calculated from the best-fit curve from 0x0A to 0xFFF. The best-fit curve method is used to deliver coefficients "a" and "b" of the first order equation: $y = a + b \times x$. $V_{DAC12 \times OUT} = E_O + (1 + E_G) \times (V_{eREF+}/4095) \times DAC12_xDAT$, DAC12IR = 1.
 - 2. The offset calibration works on the output operational amplifier. Offset calibration is triggered setting bit DAC12CALON.
 - 3. The offset calibration can be done if DAC12AMPx = {2, 3, 4, 5, 6, 7}. The output operational amplifier is switched off with DAC12AMPx = {0, 1}. It is recommended that the DAC12 module be configured prior to initiating calibration. Port activity during calibration may affect accuracy and is not recommended.

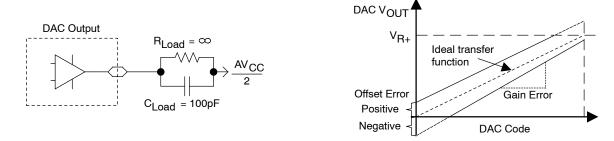
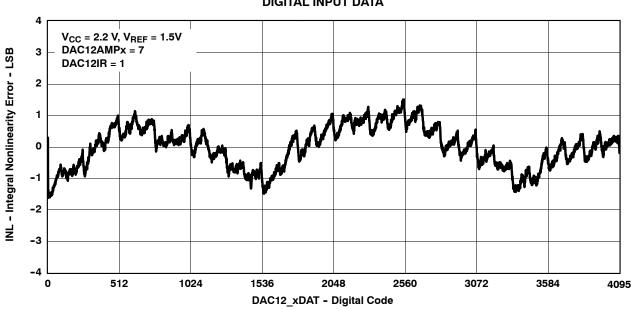


Figure 41. Linearity Test Load Conditions and Gain/Offset Definition

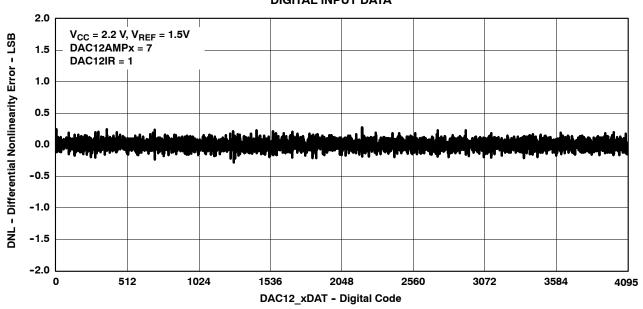
electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

typical characteristics - 12-bit DAC, linearity specifications





TYPICAL DNL ERROR vs DIGITAL INPUT DATA





electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

12-bit DAC output specifications

	PARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	UNIT
Vo	Output voltage range (see Note 1 and Figure 44)	No Load, $Ve_{REF+} = AV_{CC}$, DAC12_xDAT = 0h, DAC12IR = 1, DAC12AMPx = 7		0		0.005	
		No Load, Ve _{REF+} = AV _{CC} , DAC12_xDAT = 0FFFh, DAC12IR = 1, DAC12AMPx = 7	0.001/0.1/	AV _{CC} -0.05		AV_{CC}	V
		R_{Load} = 3 k Ω , Ve_{REF+} = AV $_{CC}$, DAC12_xDAT = 0h, DAC12IR = 1, DAC12AMPx = 7	2.2 V/3 V	0		0.1	V
		R_{Load} = 3 k Ω , Ve_{REF+} = AV $_{CC}$, DAC12_xDAT = 0FFFh, DAC12IR = 1, DAC12AMPx = 7		AV _{CC} -0.13		AV_{CC}	
C _{L(DAC12)}	Max DAC12 load capacitance		2.2 V/3 V			100	pF
			2.2V	-0.5		+0.5	
I _{L(DAC12)}	Max DAC12 load current		3V	-1.0		+1.0	mA
		R_{Load} = 3 k Ω , $V_{O/P(DAC12)}$ = 0 V, DAC12AMPx = 7, DAC12_xDAT = 0h			150	250	
R _{O/P(DAC12)}	Output resistance (see Figure 44)	R_{Load} = 3 k Ω , $V_{O/P(DAC12)}$ = A V_{CC} , DAC12AMPx = 7, DAC12_xDAT = 0FFFh	2.2 V/3 V		150	250	Ω
		$\begin{array}{c} R_{Load} = 3 \; k\Omega, \\ 0.3 \; V \leq V_{O/P(DAC12)} \leq AV_{CC} - 0.3 \; V, \\ DAC12AMPx = 7 \end{array}$			1	4	

NOTE 1: Data is valid after the offset calibration of the output amplifier.

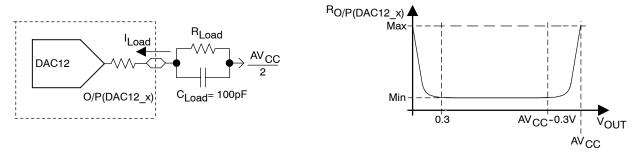


Figure 44. DAC12_x Output Resistance Tests

electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

12-bit DAC reference input specifications

PARAMETER		TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
Ve _{REF+}	Reference input voltage	DAC12IR = 0, (see Notes 1 and 2)	0.07//07/		AV _{CC} /3	AV _{CC} +0.2	.,
	range	DAC12IR = 1, (see Notes 3 and 4)	2.2 V/3 V		AVcc	AVcc+0.2	V
		DAC12_0 IR = DAC12_1 IR = 0	_	20			MΩ
		DAC12_0 IR = 1, DAC12_1 IR = 0			4.0		
Ri _(VREF+) ,		DAC12_0 IR = 0, DAC12_1 IR = 1	2.2 V/3 V	40	48	56	
Ri _(VeREF+)		DAC12_0 IR = DAC12_1 IR = 1 DAC12_0 SREFx = DAC12_1 SREFx (see Note 5)		20	24	28	kΩ

NOTES: 1. For a full-scale output, the reference input voltage can be as high as 1/3 of the maximum output voltage swing (AV_{CC}).

- 2. The maximum voltage applied at reference input voltage terminal Ve_{REF+} = [AV_{CC} V_{E(O)}] / [3*(1 + E_G)].
- 3. For a full-scale output, the reference input voltage can be as high as the maximum output voltage swing (AV_{CC}).
- 4. The maximum voltage applied at reference input voltage terminal Ve_{REF+} = [AV_{CC} V_{E(O)}] / (1 + E_G).
- 5. When DAC12IR = 1 and DAC12SREFx = 0 or 1 for both channels, the reference input resistive dividers for each DAC are in parallel reducing the reference input resistance.

12-bit DAC dynamic specifications, V_{ref} = V_{CC}, DAC12IR = 1 (see Figure 45 and Figure 46)

P	ARAMETER	TES.	T CONDITIONS	VCC	MIN	TYP	MAX	UNIT
	DAC12_xDAT = 800h,	DAC12AMPx = $0 \rightarrow \{2, 3, 4\}$			60	120		
t _{ON}	DAC12 on-time	$Error_{V(O)} < \pm 0.5 LSB$ (see Note 1 and	$DAC12AMPx = 0 \rightarrow \{5, 6\}$	2.2 V/3 V		15	30	μs
		Figure 45)	DAC12AMPx = 0 → 7			6	12	
			DAC12AMPx = 2			100	200	
t _{S(FS)}	Settling time, FS) full scale	DAC12_xDAT = 80h→ F7Fh→ 80h	DAC12AMPx = 3, 5	2.2 V/3 V		40	80	μs
· / Iuli scale		DAC12AMPx = 4, 6, 7			15	30		
	0	DAC12_xDAT = 3F8h→ 408h→ 3F8h BF8h→ C08h→ BF8h	DAC12AMPx = 2	2.2 V/3 V		5		μs
ts(C-C)	Settling time, code to code		DAC12AMPx = 3, 5			2		
	0000 10 0000		DAC12AMPx = 4, 6, 7			1		
		DAG40 DAT	DAC12AMPx = 2		0.05	0.12		V/μs
SR	Slew rate	DAC12_xDAT = 80h→ F7Fh→ 80h	DAC12AMPx = 3, 5	2.2 V/3 V	0.35	0.7		
		0011-21 71 11-2 0011	DAC12AMPx = 4, 6, 7		1.5	2.7		
		5.0.0	DAC12AMPx = 2	2.2 V/3 V		600		
	Glitch energy, full scale	DAC12_xDAT = 80h→ F7Fh→ 80h	DAC12AMPx = 3, 5			150		nV-s
	iuii scale 80fi→ F/F	33 4 77 11 4 3011	DAC12AMPx = 4, 6, 7			30		

NOTES: 1. R_{Load} and C_{Load} are connected to AV_{SS} (not AV_{CC}/2) in Figure 45.

2. Slew rate applies to output voltage steps ≥ 200 mV.

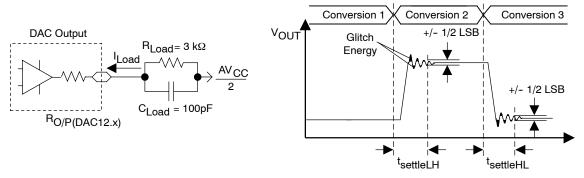


Figure 45. Settling Time and Glitch Energy Testing



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

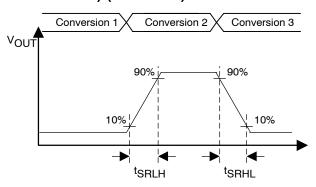


Figure 46. Slew Rate Testing

12-bit DAC, dynamic specifications (continued) (T_A = 25°C, unless otherwise noted)

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
		DAC12AMPx = {2, 3, 4}, DAC12SREFx = 2, DAC12IR = 1, DAC12_xDAT = 800h		40			
BW _{-3dB}	3-dB bandwidth, $V_{DC} = 1.5V$, $V_{AC} = 0.1 V_{PP}$ (see Figure 47)	DAC12AMPx = {5, 6}, DAC12SREFx = 2, DAC12IR = 1, DAC12_xDAT = 800h	2.2 V/3 V	180			kHz
	(see Figure 47)	DAC12AMPx = 7, DAC12SREFx = 2, DAC12IR = 1, DAC12_xDAT = 800h		550			
	Channel-to-channel crosstalk	DAC12_0DAT = 800h, No load, DAC12_1DAT = 80h<->F7Fh, R_{Load} = 3 k Ω , f_{DAC12_1OUT} = 10 kHz, Duty cycle = 50%	0.01/01/		-80		4D
	(see Note 1 and Figure 48)	DAC12_0DAT = 80h<->F7Fh, R_{Load} = 3 $k\Omega$, DAC12_1DAT = 800h, No load, f_{DAC12_0OUT} = 10 kHz, Duty cycle = 50%	2.2 V/3 V		-80		dB

NOTE 1: $R_{LOAD} = 3 \text{ k}\Omega$, $C_{LOAD} = 100 \text{ pF}$

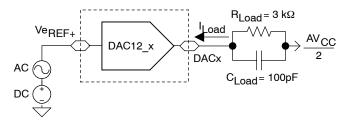


Figure 47. Test Conditions for 3-dB Bandwidth Specification

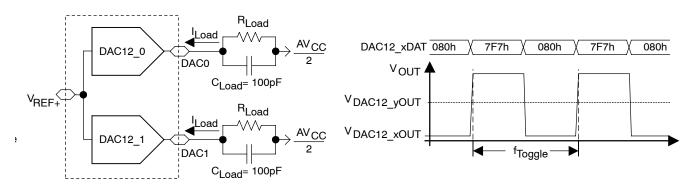


Figure 48. Crosstalk Test Conditions



SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

flash memory

	PARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	UNIT
V _{CC(PGM/ERASE)}	Program and erase supply voltage			2.2		3.6	V
f _{FTG}	Flash Timing Generator frequency			257		476	kHz
I _{PGM}	Supply current from DV _{CC} during program		2.2 V/ 3.6 V		3	5	mA
I _{ERASE}	Supply current from DV _{CC} during erase		2.2 V/ 3.6 V		3	7	mA
t _{CPT}	Cumulative program time	See Note 1	2.2 V/ 3.6 V			4	ms
t _{CMErase}	Cumulative mass erase time	See Note 2	2.2 V/ 3.6 V	200			ms
	Program/Erase endurance			10 ⁴	10 ⁵		cycles
t _{Retention}	Data retention duration	T _J = 25°C		100			years
t _{Word}	Word or byte program time	See Note 3			35		t _{FTG}
t _{Block, 0}	Block program time for first byte or word	See Note 3			30		t _{FTG}
t _{Block, 1-63}	Block program time for each additional byte or word	See Note 3			21		t _{FTG}
t _{Block, End}	Block program end-sequence wait time	See Note 3			6		t _{FTG}
t _{Mass Erase}	Mass erase time (see Note 4)	See Note 3			10593		t _{FTG}
t _{Seg Erase}	Segment erase time	See Note 3			4819		t _{FTG}

- NOTES: 1. The cumulative program time must not be exceeded when writing to a 64-byte flash block. This parameter applies to all programming methods: individual word/byte write and block write modes.
 - 2. The mass erase duration generated by the flash timing generator is at least 11.1 ms (= 5297x1/f_{FTG},max = 5297 × 1/476 kHz). To achieve the required cumulative mass erase time, the Flash Controller's mass erase operation can be repeated until this time is met. A worst case minimum of 19 cycles is required.
 - 3. These values are hardwired into the Flash Controller's state machine ($t_{FTG} = 1/f_{FTG}$).
 - 4. To erase the complete code area, the mass erase must be performed once with a dummy address in the range of the lower 64-kB flash addresses and once with the dummy address in the upper 64-kB flash addresses.

RAM

	PARAMETER	TEST CONDITIONS	MIN MAX	UNIT
VRAMh	See Note 1	CPU halted	1.6	V

NOTE 1: This parameter defines the minimum supply voltage when the data in program memory RAM remain unchanged. No program execution should take place during this supply voltage condition.

MSP430x241x, MSP430x261x MIXED SIGNAL MICROCONTROLLER

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

JTAG interface

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
·	TCK input frequency	Coo Noto 1	2.2 V	0		5	N 41 1-
TCK		See Note 1	3 V	0		10	MHz
R _{Internal}	Internal pullup resistance on TMS, TCK, TDI/TCLK	See Note 2	2.2 V/ 3 V	25	60	90	kΩ

NOTES: 1. f_{TCK} may be restricted to meet the timing requirements of the module selected.

JTAG fuse (see Note 1)

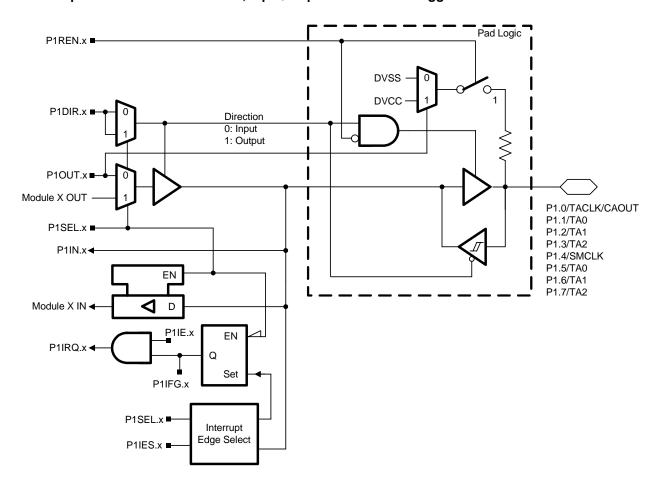
	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
V _{CC(FB)}	Supply voltage during fuse-blow condition	T _A = 25°C	2.5		V
V_{FB}	Voltage level on TDI/TCLK for fuse blow (F versions)		6	7	V
I _{FB}	Supply current into TDI/TCLK during fuse blow			100	mA
t _{FB}	Time to blow fuse			1	ms

NOTE 1: Once the fuse is blown, no further access to the MSP430 JTAG/Test and emulation features is possible. The JTAG block is switched to bypass mode.

^{2.} TMS, TDI/TCLK, and TCK pullup resistors are implemented in all versions.

APPLICATION INFORMATION

Port P1 pin schematic: P1.0 to P1.7, input/output with Schmitt trigger



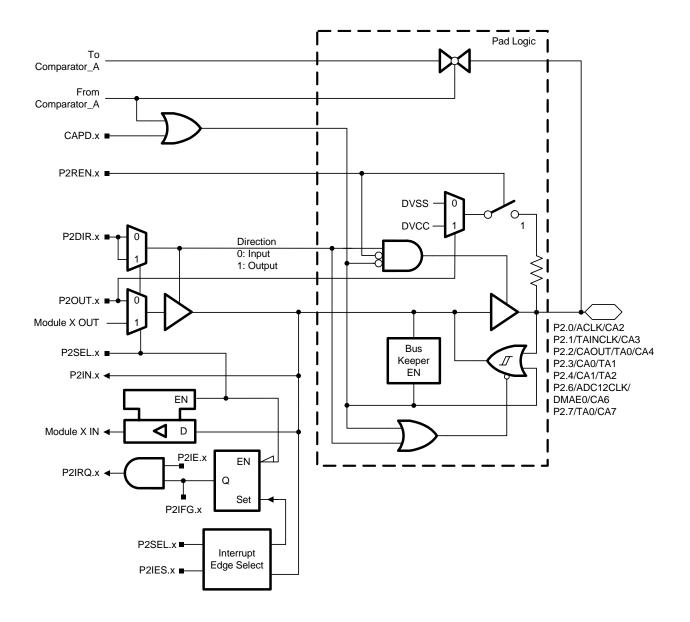
MSP430x241x, MSP430x261x MIXED SIGNAL MICROCONTROLLER

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

Port P1 (P1.0 to P1.7) pin functions

DIN NAME (D4)			CONTROL B	ITS / SIGNALS
PIN NAME (P1.X)	X	FUNCTION	P1DIR.x	P1SEL.x
P1.0/TACLK	0	P1.0 (I/O)	l: 0; O: 1	0
		Timer_A3.TACLK	0	1
		CAOUT	1	1
P1.1/TA0	1	P1.1 (I/O)	l: 0; O: 1	0
		Timer_A3.CCI0A	0	1
		Timer_A3.TA0	1	1
P1.2/TA1	2	P1.2 (I/O)	l: 0; O: 1	0
		Timer_A3.CCI0A	0	1
		Timer_A3.TA0	1	1
P1.3/TA2	3	P1.3 (I/O)	l: 0; O: 1	0
		Timer_A3.CCI0A	0	1
		Timer_A3.TA0	1	1
P1.4/SMCLK	4	P1.4 (I/O)	l: 0; O: 1	0
		SMCLK	1	1
P1.5/TA0	5	P1.5 (I/O)	l: 0; O: 1	0
		Timer_A3.CCI0A	0	1
		Timer_A3.TA0	1	1
P1.6/TA1	6	P1.6 (I/O)	l: 0; O: 1	0
		Timer_A3.CCI0A	0	1
		Timer_A3.TA1	1	1
P1.7/TA2	7	P1.7 (I/O)	I: 0; O: 1	0
		Timer_A3.CCI0A	0	1
		Timer A3.TA2	1	1

Port P2 pin schematic: P2.0 to P2.4, P2.6, and P2.7, input/output with Schmitt trigger



MSP430x241x, MSP430x261x MIXED SIGNAL MICROCONTROLLER

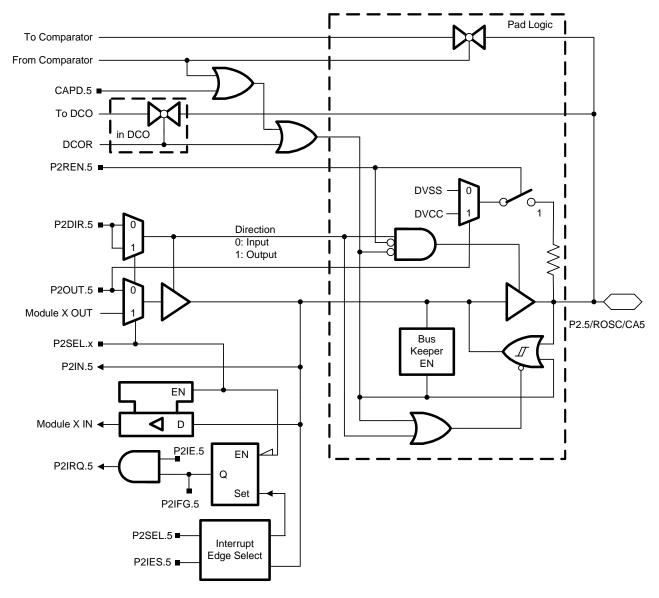
SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

Port P2.0, P2.3, P2.4, P2.6 and P2.7 pin functions

DINI NIAME (DO VI			CONT	TROL BITS / SIGNALS		
PIN NAME (P2.X)	X	FUNCTION	CAPD.x	P2DIR.x	P2SEL.x	
P2.0/ACLK/CA2	0	P2.0 (I/O)	0	I: 0; O: 1	0	
		ACLK	0	1	1	
		CA2	1	X	Х	
P2.1/TAINCLK/CA3	1	P2.1 (I/O)	0	I: 0; O: 1	0	
		Timer_A3.INCLK	0	0	1	
		DV _{SS}	0	1	1	
		CA3	1	Х	Х	
P2.2/CAOUT/TA0/	2	P2.2 (I/O)	0	I: 0; O: 1	0	
CA4		CAOUT	0	1	1	
		TA0	0	0	1	
		CA4	1	Х	Х	
P2.3/CA0/TA1	3	P2.3 (I/O)	0	I: 0; O: 1	0	
		Timer_A3.TA1	0	1	1	
		CA0	1	X	Х	
P2.4/CA1/TA2	4	P2.4 (I/O)	0	I: 0; O: 1	0	
		Timer_A3.TA2	0	1	Х	
		CA1	1	X	1	
P2.6/ADC12CLK/	6	P2.6 (I/O)	0	I: 0; O: 1	0	
DMAE0/CA6		ADC12CLK	0	1	1	
		DMAE0	0	0	1	
		CA6	1	Х	Х	
P2.7/TA0/CA7	7	P2.7 (I/O)	0	I: 0; O: 1	0	
		Timer_A3.TA0	0	1	1	
		CA7	1	Х	Х	

NOTE: X: Don't care

Port P2 pin schematic: P2.5, input/output with Schmitt trigger



Port P2.5 pin functions

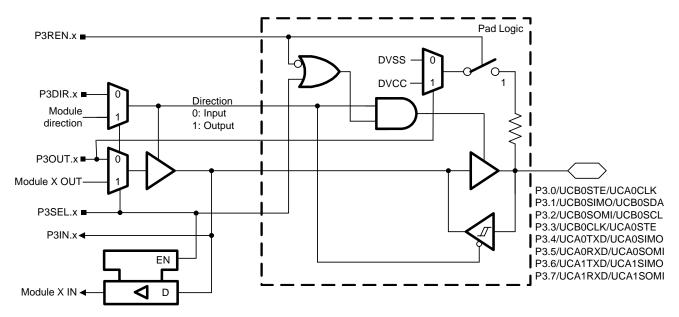
DIN NAME (DO V)		FUNCTION	CONTROL BITS / SIGNALS			
PIN NAME (P2.X)	X		CAPD	DCOR	P2DIR.5	P2SEL.5
P2.5/R _{OSC} /CA5	5	P2.5 (I/O)	0	0	I: 0; O: 1	0
		R _{OSC} (see Note 2)	0	1	X	Х
		DV _{SS}	0	0	1	1
		CA5	1 or selected	0	Х	Х

NOTES: 1. X: Don't care

2. If Rosc is used it is connected to an external resistor.



Port P3 pin schematic: P3.0 to P3.7, input/output with Schmitt trigger



Port P3.0 to P3.7 pin functions

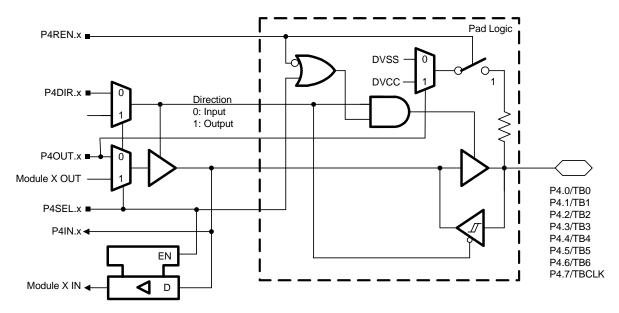
DIN NAME (DO VO			CONTROL BIT	rs / Signals
PIN NAME (P3.X)	X	FUNCTION	P3DIR.x	P3SEL.x
P3.0/UCB0STE/	0	P3.0 (I/O)	l: 0; O: 1	0
UCA0CLK		UCB0STE/UCA0CLK (see Note 2 and 4)	X	1
P3.1/UCB0SIMO/	1	P3.1 (I/O)	I: 0; O: 1	0
UCB0SDA		UCB0SIMO/UCB0SDA (see Note 2 and 3)	X	1
P3.2/UCB0SOMI/	2	P3.2 (I/O)	I: 0; O: 1	0
UCB0SCL		UCB0SOMI/UCB0SCL (see Note 2 and 3)	X	1
P3.3/UCB0CLK/	3	P3.3 (I/O)	I: 0; O: 1	0
UCA0STE		UCB0CLK/UCA0STE (see Note 2)	X	1
P3.4/UCA0TXD/	4	P3.4 (I/O)	l: 0; O: 1	0
UCA0SIMO		UCA0TXD/UCA0SIMO (see Note 2)	X	1
P3.5/UCA0RXD/	5	P3.5 (I/O)	l: 0; O: 1	0
UCA0SOMI		UCA0RXD/UCA0SOMI (see Note 2)	X	1
P3.6/UCA1TXD/	6	P3.6 (I/O)	l: 0; O: 1	0
UCA1SIMO		UCA1TXD/UCA1SIMO (see Note 2)	X	1
P3.7/UCA1RXD/	7	P3.7 (I/O)	I: 0; O: 1	0
UCA1SOMI		UCA1RXD/UCA1SOMI (see Note 2)	X	1

NOTES: 1. X: Don't care

- 2. The pin direction is controlled by the USCI module.
- 3. In case the I2C functionality is selected the output drives only the logical 0 to V_{SS} level.
- 4. UCA0CLK function takes precedence over UCB0STE function. If the pin is required as UCA0CLK input or output USCI A0/B0 will be forced to 3-wire SPI mode if 4-wire SPI mode is selected.



Port P4 pin schematic: P4.0 to P4.7, input/output with Schmitt trigger

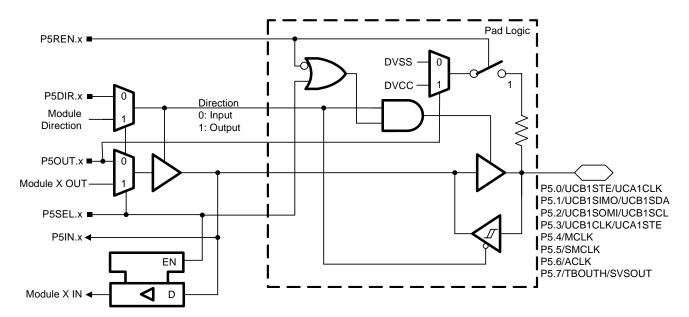


Port P4.0 to P4.7 pin functions

DINI NAME (DA VO			CONTROL BI	rs / Signals
PIN NAME (P4.X)	X	FUNCTION	P4DIR.x	P4SEL.x
P4.0/TB0	0	P4.0 (I/O)	I: 0; O: 1	0
		Timer_B7.CCl0A and Timer_B7.CCl0B	0	1
		Timer_B7.TB0	1	1
P4.1/TB1	1	P4.1 (I/O)	I: 0; O: 1	0
		Timer_B7.CCl1A and Timer_B7.CCl1B	0	1
		Timer_B7.TB1	1	1
P4.2/TB2	2	P4.2 (I/O)	I: 0; O: 1	0
		Timer_B7.CCl2A and Timer_B7.CCl2B	0	1
		Timer_B7.TB2	1	1
P4.3/TB3	3	P4.3 (I/O)	I: 0; O: 1	0
		Timer_B7.CCl3A and Timer_B7.CCl3B	0	1
		Timer_B7.TB3	1	1
P4.4/TB4	4	P4.4 (I/O)	I: 0; O: 1	0
		Timer_B7.CCl4A and Timer_B7.CCl4B	0	1
		Timer_B7.TB4	1	1
P4.5/TB5	5	P4.5 (I/O)	l: 0; O: 1	0
		Timer_B7.CCl5A and Timer_B7.CCl5B	0	1
		Timer_B7.TB5	1	1
P4.6/TB6	6	P4.6 (I/O)	I: 0; O: 1	0
		Timer_B7.CCl6A and Timer_B7.CCl6B	0	1
		Timer_B7.TB6	1	1
P4.7/TBCLK	7	P4.7 (I/O)	l: 0; O: 1	0
		Timer_B7.TBCLK	1	1



Port P5 pin schematic: P5.0 to P5.7, input/output with Schmitt trigger



Port P5.0 to P5.7 pin functions

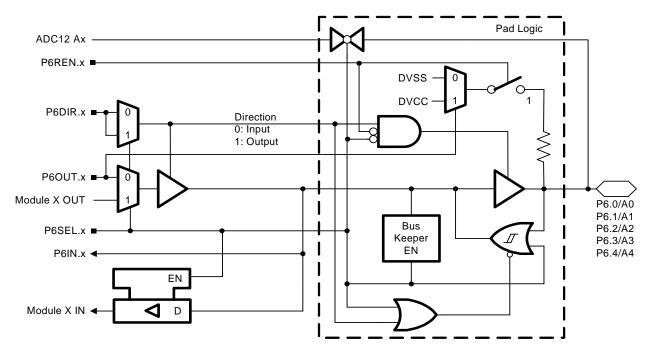
DIN NAME (DE VO		FUNCTION	CONTROL BI	TS / SIGNALS
PIN NAME (P5.X)	X	FUNCTION	P5DIR.x	P5SEL.x
P5.0/UCB1STE/	0	P5.0 (I/O)	I: 0; O: 1	0
UCA1CLK		UCB1STE/UCA1CLK (see Note 2 and 4)	X	1
P5.1/UCB1SIMO/	1	P5.1 (I/O)	I: 0; O: 1	0
UCB1SDA		UCB1SIMO/UCB1SDA (see Note 2 and 3)	X	1
P5.2/UCB1SOMI/	2	P5.2 (I/O)	I: 0; O: 1	0
UCB1SCL		UCB1SOMI/UCB1SCL (see Note 2 and 3)	Х	1
P5.3/UCB1CLK/	3	P5.3 (I/O)	I: 0; O: 1	0
UCA1STE		UCB1CLK/UCA1STE (see Note 2)	X	1
P5.4/MCLK	4	P5.0 (I/O)	I: 0; O: 1	0
		MCLK	1	1
P5.5/SMCLK	5	P5.1 (I/O)	I: 0; O: 1	0
		SMCLK	1	1
P5.6/ACLK	6	P5.2 (I/O)	I: 0; O: 1	0
		ACLK	1	1
P5.7/TBOUTH/	7	P5.7 (I/O)	I: 0; O: 1	0
SVSOUT		ТВОИТН	0	1
		SVSOUT	1	1

NOTES: 1. X: Don't care

- 2. The pin direction is controlled by the USCI module.
- 3. In case the I2C functionality is selected the output drives only the logical 0 to V_{SS} level.
- 4. UCA1CLK function takes precedence over UCB1STE function. If the pin is required as UCA1CLK input or output USCI A1/B1 will be forced to 3-wire SPI mode if 4-wire SPI mode is selected.



Port P6 pin schematic: P6.0 to P6.4, input/output with Schmitt trigger



Port P6.0 to P6.4 pin functions

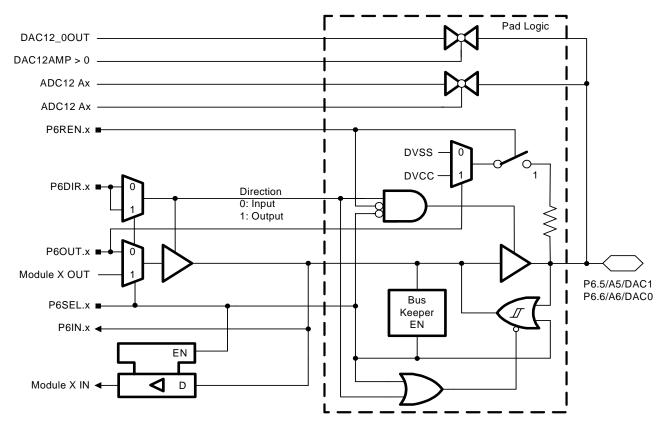
DIN NAME (DC V)			CONTROL BIT	rs / Signals
PIN NAME (P6.X)	X	FUNCTION	P6DIR.x	P6SEL.x
P6.0/A0	0	P6.0 (I/O)	I: 0; O: 1	0
		A0 (see Note 2)	Х	Х
P6.1/A1	1	P6.1 (I/O)	I: 0; O: 1	0
		A1 (see Note 2)	Х	X
P6.2/A2	2	P6.2 (I/O)	I: 0; O: 1	0
		A2 (see Note 2)	Х	Х
P6.3/A3	3	P6.3 (I/O)	I: 0; O: 1	0
		A3 (see Note 2)	Х	Х
P6.4/A4	4	P6.4 (I/O)	I: 0; O: 1	0
		A4 (see Note 2)	Х	Х

NOTES: 1. X: Don't care

2. The ADC12 channel Ax is connected to AVss internally if not selected.



Port P6 pin schematic: P6.5 and P6.6, input/output with Schmitt trigger



Port P6.5 to P6.6 pin functions

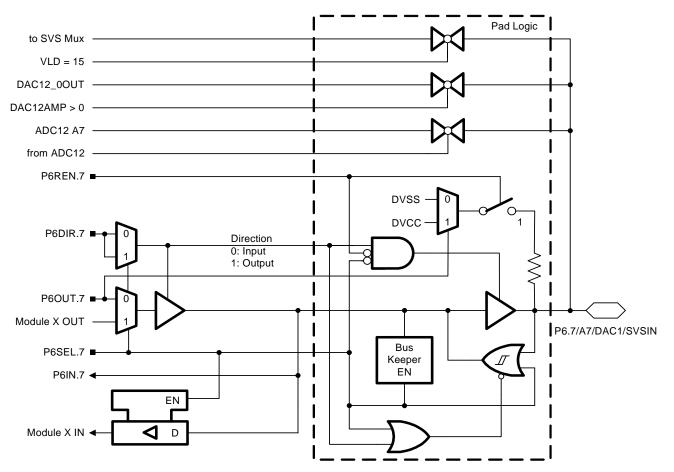
			CON	CONTROL BITS / SIGNALS				
PIN NAME (P6.X)	X	FUNCTION	P6DIR.x	P6SEL.x	CAPD.x or DAC12AMP > 0			
P6.5/A5/DAC1†	5	P6.5 (I/O)	I: 0; O: 1	0	0			
		DV _{SS}	1	1	0			
		A5 (see Note 2)	X	X	1			
		DAC1 (DA12OPS= 1, see Note 3)	Х	X	1			
P6.6/A6/DAC0†	6	P6.6 (I/O)	I: 0; O: 1	0	0			
		DV _{SS}	1	1	0			
		A6 (see Note 2)	Х	X	1			
		DAC0 (DA12OPS= 0, see Note 3)	X	X	1			

† MSP430F261x devices only

NOTES: 1. X: Don't care

- 2. The ADC12 channel Ax is connected to AVss internally if not selected.
- 3. The DAC outputs are floating if not selected.

Port P6 pin schematic: P6.7, input/output with Schmitt trigger



Port P6.7 pin functions

PIN NAME (P6.X)	,	FUNCTION	CONTROL BITS / SIGNALS		
	Х	FUNCTION	P6DIR.x	P6SEL.x	
P6.7/A7/DAC1†/	7	P6.7 (I/O)	I: 0; O: 1	0	
SVSIN†		DV _{SS}	1	1	
		A7 (see Note 2)	X	X	
		DAC1 (DA12OPS= 0, see Note 3)	X	X	
		SVSIN (VLD = 15)	Х	X	

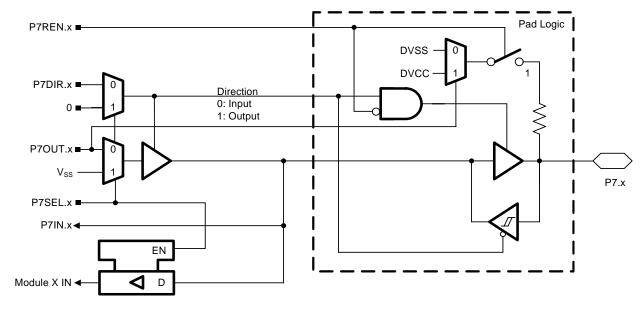
NOTES: 1. X: Don't care

- 2. The ADC12 channel Ax is connected to AVss internally if not selected.
- 3. The DAC outputs are floating if not selected.



[†] MSP430F261x devices only

Port P7 pin schematic: P7.0 to P7.7, input/output with Schmitt trigger[†]

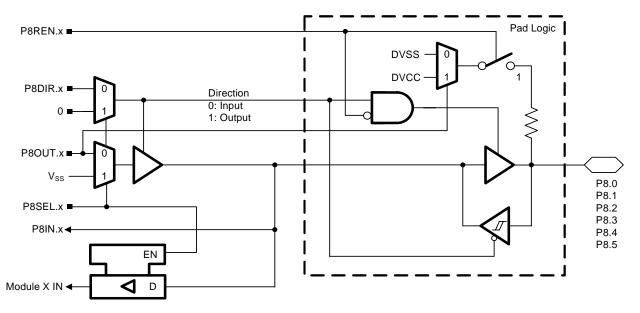


Port P7.0 to P7.7 pin functions[†]

DINI NIAME (DZ V)		FUNCTION	CONTROL BI	CONTROL BITS / SIGNALS		
PIN NAME (P7.X)	X	FUNCTION	P7DIR.x	P7SEL.x		
P7.0	0	P7.0 (I/O)	l: 0; O: 1	0		
		Input	X	1		
P7.1	1	P7.1 (I/O)	l: 0; O: 1	0		
		Input	X	1		
P7.2	2	P7.2 (I/O)	l: 0; O: 1	0		
		Input	X	1		
P7.3	3	P7.3 (I/O)	I: 0; O: 1	0		
		Input	X	1		
P7.4	4	P7.4 (I/O)	l: 0; O: 1	0		
		Input	X	1		
P7.5	5	P7.5 (I/O)	l: 0; O: 1	0		
		Input	X	1		
P7.6	6	P7.6 (I/O)	l: 0; O: 1	0		
		Input	X	1		
P7.7	7	P7.7 (I/O)	l: 0; O: 1	0		
		Input	X	1		

^{† 80-}pin devices only

Port P8 pin schematic: P8.0 to P8.5, input/output with Schmitt trigger†



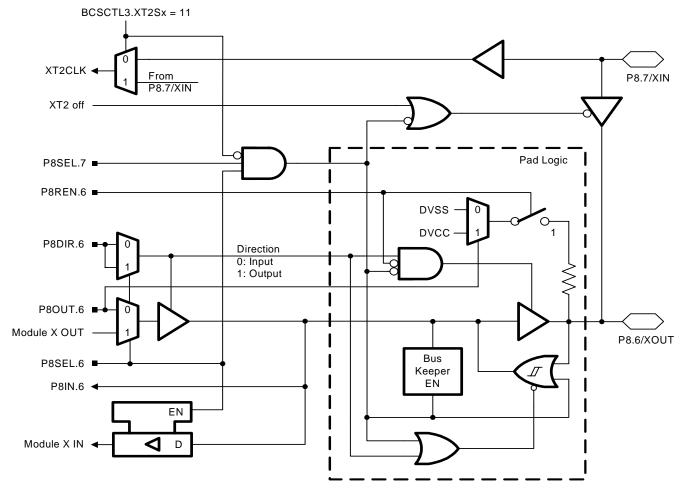
Port P8.0 to P8.5 pin functions†

PIN NAME (P8.X)		FUNCTION	CONTROL BITS / SIGNALS		
PIN NAME (P8.X)	Х	FUNCTION	P8DIR.x	P8SEL.x	
P8.0	0	P8.0 (I/O)	I: 0; O: 1	0	
		Input	Х	1	
P8.1		P8.1 (I/O)	I: 0; O: 1	0	
		Input	Х	1	
P8.2	2	P8.2 (I/O)	I: 0; O: 1	0	
		Input	X	1	
P8.3	3	P8.3 (I/O)	I: 0; O: 1	0	
		Input	Х	1	
P8.4	4	P8.4 (I/O)	I: 0; O: 1	0	
		Input	Х	1	
P8.5	5	P8.5 (I/O)	I: 0; O: 1	0	
		Input	Х	1	

^{† 80-}pin devices only



Port P8 pin schematic: P8.6, input/output with Schmitt trigger†



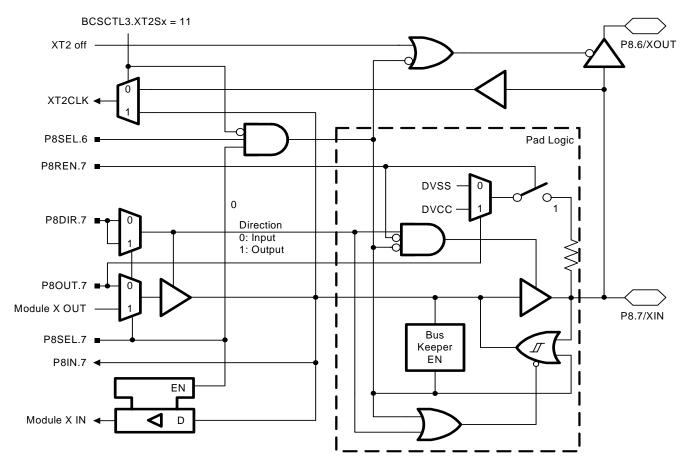
Port P8.6 pin functions†

PIN NAME (P8.X)		FUNCTION	CONTROL BITS / SIGNALS		
PIN NAME (P8.X)		FUNCTION	P8DIR.x	P8SEL.x	
P8.6/XOUT	6	P8.6 (I/O)	I: 0; O: 1	0	
		XOUT (default)	0	1	
		DV _{SS}	1	1	

^{† 80-}pin devices only

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

Port P8 pin schematic: P8.7, input/output with Schmitt trigger[†]



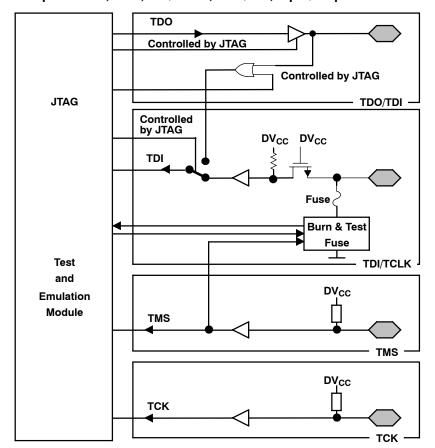
Port P8.7 pin functions†

PIN NAME (P8.X)	x	FUNCTION	CONTROL BITS / SIGNALS		
PIN NAME (PO.A)		FUNCTION	P8DIR.x	P8SEL.x	
P8.7/XIN	7	P8.7 (I/O)	I: 0; O: 1	0	
		XIN (default)	0	1	
		V_{SS}	1	1	

^{† 80-}pin devices only

APPLICATION INFORMATION

JTAG pins: TMS, TCK, TDI/TCLK, TDO/TDI, input/output with Schmitt trigger



During Programming Activity and During Blowing of the Fuse, Pin TDO/TDI Is Used to Apply the Test Input Data for JTAG Circuitry SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

APPLICATION INFORMATION

JTAG fuse check mode

MSP430 devices that have the fuse on the TDI/TCLK terminal have a fuse check mode that tests the continuity of the fuse the first time the JTAG port is accessed after a power-on reset (POR). When activated, a fuse check current, I_{TF} , of 1 mA at 3 V, 2.5 mA at 5 V can flow from the TDI/TCLK pin to ground if the fuse is not burned. Care must be taken to avoid accidentally activating the fuse check mode and increasing overall system power consumption.

Activation of the fuse check mode occurs with the first negative edge on the TMS pin after power up or if the TMS is being held low during power up. The second positive edge on the TMS pin deactivates the fuse check mode. After deactivation, the fuse check mode remains inactive until another POR occurs. After each POR the fuse check mode has the potential to be activated.

The fuse check current will only flow when the fuse check mode is active and the TMS pin is in a low state (see Figure 49). Therefore, the additional current flow can be prevented by holding the TMS pin high (default condition).

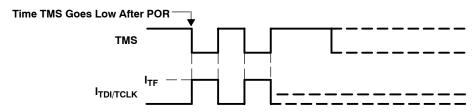


Figure 49. Fuse Check Mode Current

MSP430x241x, MSP430x261x MIXED SIGNAL MICROCONTROLLER

SLAS541A - JUNE 2007 - REVISED OCTOBER 2007

Data Sheet Revision History

LITERATURE NUMBER	SUMMARY						
SLAS541	Product Preview release.						
	Production Data release.						
	Corrected the format and the content shown on the first page.						
SLAS541A	Corrected pin number of P3.6 and P3.7 in 64-pin package in the terminal function list.						
SLASS41A	Corrected the port schematics.						
	Corrected "calibration data" section (page 20). Typos and formatting corrected.						
	Added figure "typical characteristics - LPM4 current" (page 33).						



PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
MSP430F2416TPM	ACTIVE	LQFP	PM	64	160	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2416TPMR	ACTIVE	LQFP	PM	64	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2416TPN	ACTIVE	LQFP	PN	80	119	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2416TPNR	ACTIVE	LQFP	PN	80	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2417TPM	ACTIVE	LQFP	PM	64	160	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2417TPMR	ACTIVE	LQFP	PM	64	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2417TPN	ACTIVE	LQFP	PN	80	119	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2417TPNR	ACTIVE	LQFP	PN	80	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2418TPM	ACTIVE	LQFP	PM	64	160	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2418TPMR	ACTIVE	LQFP	PM	64	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2418TPN	ACTIVE	LQFP	PN	80	119	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2418TPNR	ACTIVE	LQFP	PN	80	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2419TPM	ACTIVE	LQFP	PM	64	160	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2419TPMR	ACTIVE	LQFP	PM	64	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2419TPN	ACTIVE	LQFP	PN	80	119	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2419TPNR	ACTIVE	LQFP	PN	80	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2616TPM	ACTIVE	LQFP	PM	64	160	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2616TPMR	ACTIVE	LQFP	PM	64	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2616TPN	ACTIVE	LQFP	PN	80	119	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2616TPNR	ACTIVE	LQFP	PN	80	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2617TPM	ACTIVE	LQFP	PM	64	160	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2617TPMR	ACTIVE	LQFP	PM	64	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2617TPN	ACTIVE	LQFP	PN	80	119	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2617TPNR	ACTIVE	LQFP	PN	80	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2618TPM	ACTIVE	LQFP	PM	64	160	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR



PACKAGE OPTION ADDENDUM

2-Nov-2007

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp (3)
MSP430F2618TPMR	ACTIVE	LQFP	PM	64	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2618TPN	ACTIVE	LQFP	PN	80	119	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2618TPNR	ACTIVE	LQFP	PN	80	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2619TPM	ACTIVE	LQFP	PM	64	160	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2619TPMR	ACTIVE	LQFP	PM	64	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2619TPN	ACTIVE	LQFP	PN	80	119	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430F2619TPNR	ACTIVE	LQFP	PN	80	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PM (S-PQFP-G64)

PLASTIC QUAD FLATPACK

1



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-026
- D. May also be thermally enhanced plastic with leads connected to the die pads.

PN (S-PQFP-G80)

PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-026

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

TI products are not authorized for use in safety-critical applications (such as life support) where a failure of the TI product would reasonably be expected to cause severe personal injury or death, unless officers of the parties have executed an agreement specifically governing such use. Buyers represent that they have all necessary expertise in the safety and regulatory ramifications of their applications, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of TI products in such safety-critical applications, notwithstanding any applications-related information or support that may be provided by TI. Further, Buyers must fully indemnify TI and its representatives against any damages arising out of the use of TI products in such safety-critical applications.

TI products are neither designed nor intended for use in military/aerospace applications or environments unless the TI products are specifically designated by TI as military-grade or "enhanced plastic." Only products designated by TI as military-grade meet military specifications. Buyers acknowledge and agree that any such use of TI products which TI has not designated as military-grade is solely at the Buyer's risk, and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI products are neither designed nor intended for use in automotive applications or environments unless the specific TI products are designated by TI as compliant with ISO/TS 16949 requirements. Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, TI will not be responsible for any failure to meet such requirements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Interface	interface.ti.com	Digital Control	www.ti.com/digitalcontrol
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
RFID	www.ti-rfid.com	Telephony	www.ti.com/telephony
Low Power Wireless	www.ti.com/lpw	Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2007, Texas Instruments Incorporated